

EE-429

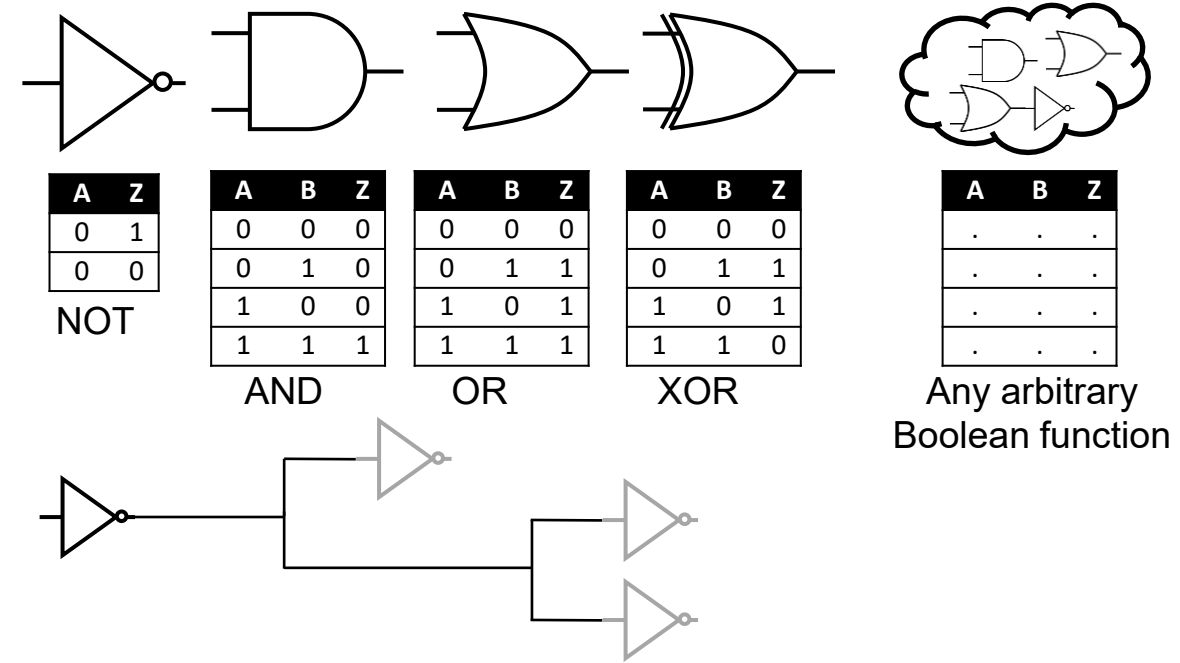
Fundamentals of VLSI Design

Basic Sequential Elements

Andreas Burg

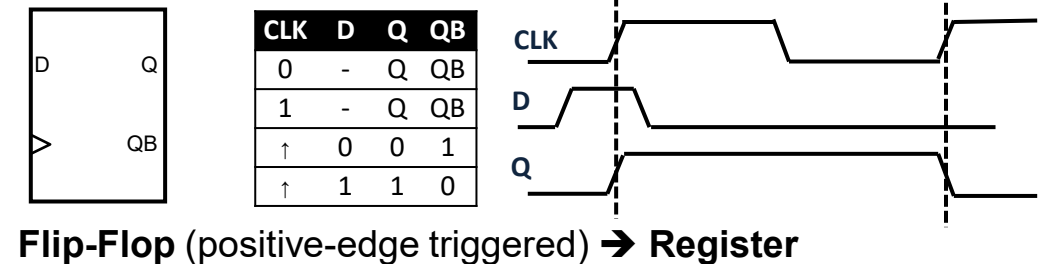
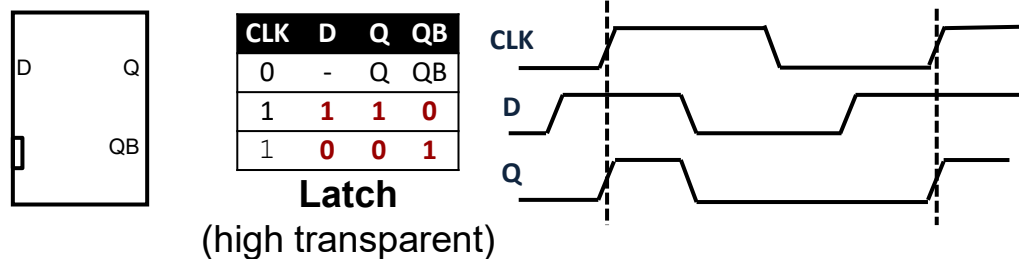
Fundamental Components of Digital Circuits

- Combinatorial logic: memoryless
 - Built from basic Boolean logic gates
 - Output is only a function of the current input
 - Combinational logic has no state
- Nets (wires): memoryless
 - Connect components, carrying logic signals
 - One input (driver) and one or multiple outputs



Storage (sequential) elements: memory

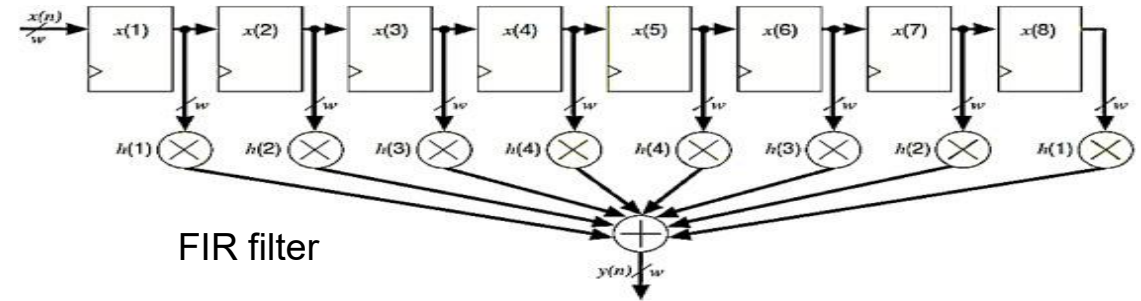
- Output depends on current input *and* on an internal state, defined by previous inputs



Why do we need Sequential Elements

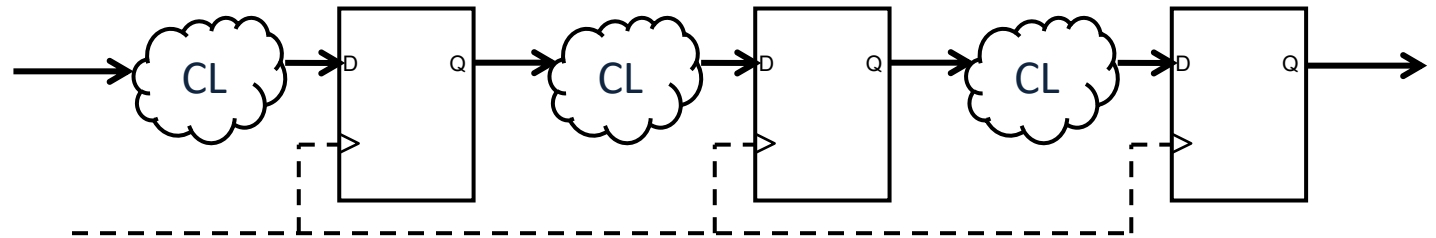
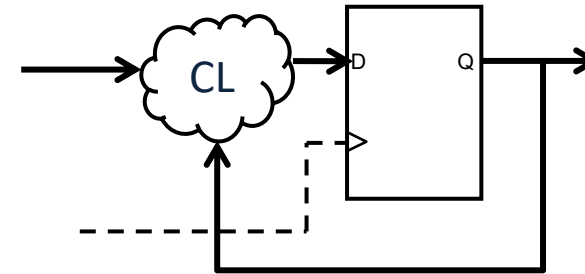
- **Functional storage:**

- Collect data that arrives in sequence and is required as a whole



- **Non-functional storage**

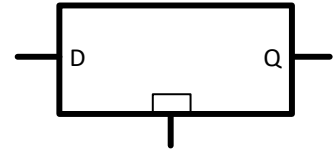
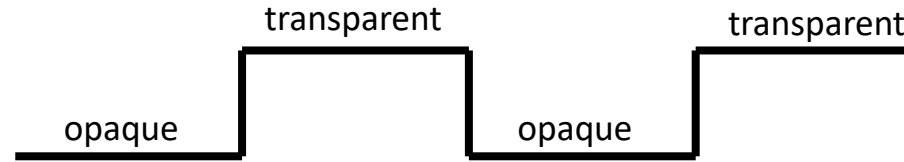
- Re-use of logic for different data over time for resource sharing
- Isolation of parts of the logic to operate in parallel through pipelining



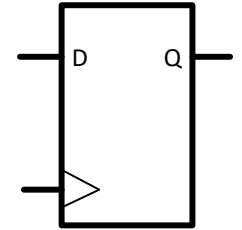
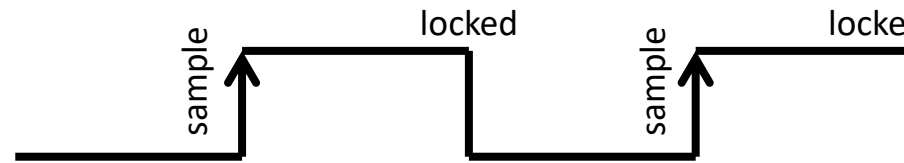
Naming Conventions

- **Two types of sequential elements:**

- a **latch** is **level sensitive**



- a **register** or a **flip-flop** is **edge-triggered**

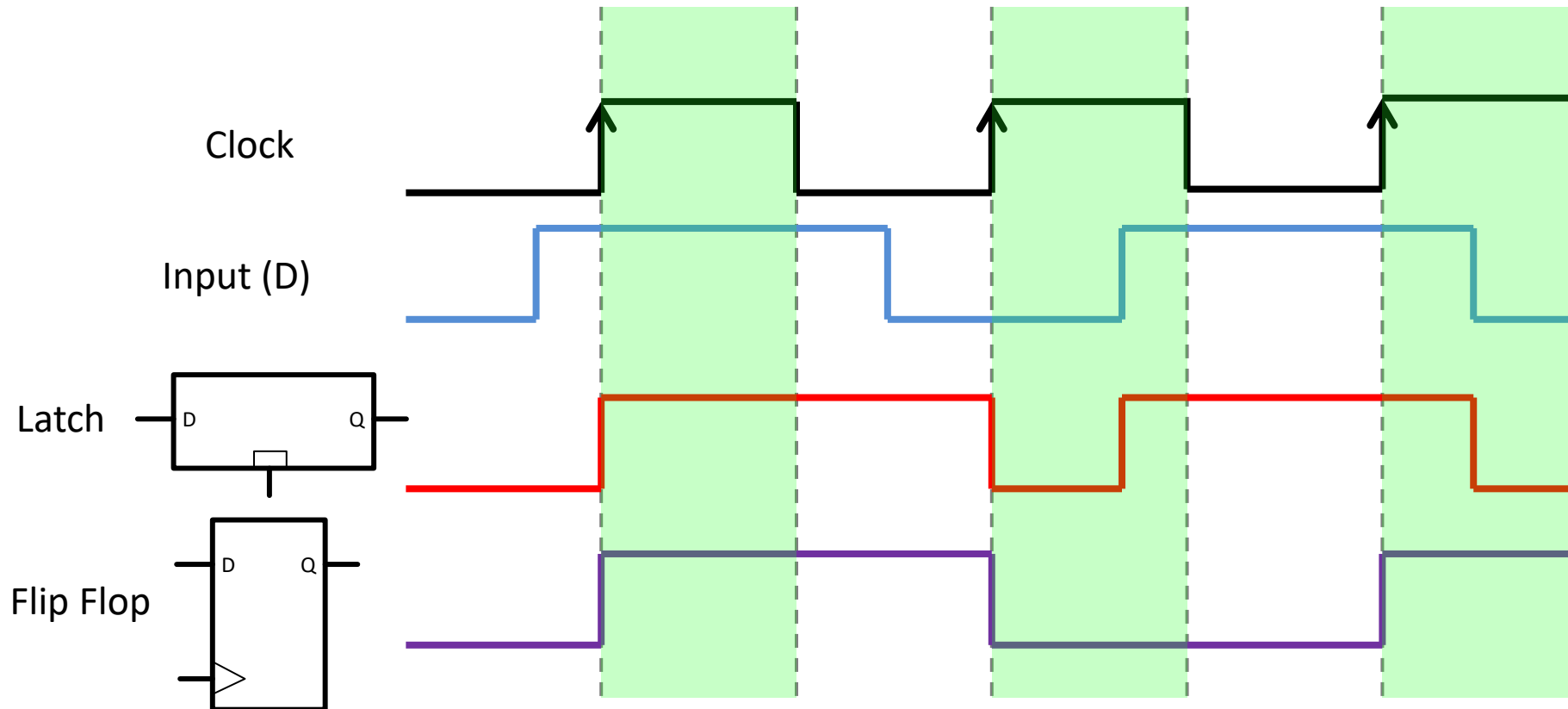


- **There are many different naming conventions**

- For instance, many books call any bi-stable element **flip-flops** (such as an SR Latch)
- However, this **leads to confusion**, so **we will use the convention above** (as used in industry).

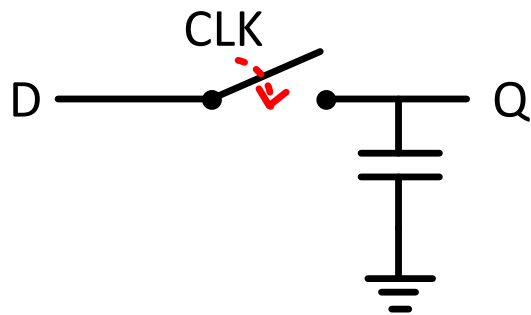
Latch Vs. Register

- A **Latch** is **transparent during one phase** of the clock and **keeps its output** (irrespective of the input) **during the other clock phase**.
- However, a **Flip Flop** only **samples the input on the edge**.

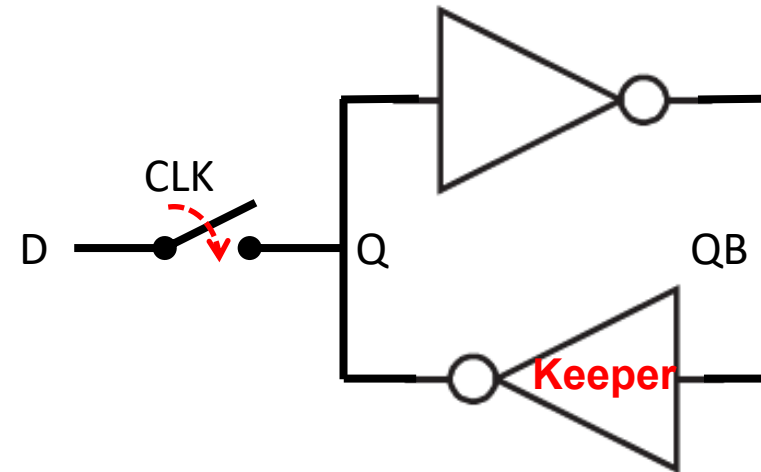


Static Vs. Dynamic Latch

- **Dynamic storage elements store data** (the state) **as charge** on a capacitance
 - No active element involved in keeping the state
 - Since charge leaks away, the stored data degrades over time
- **Static storage elements include a feedback** to constantly restore the state
 - **Active feedback** involved in keeping the state: **KEEPER**



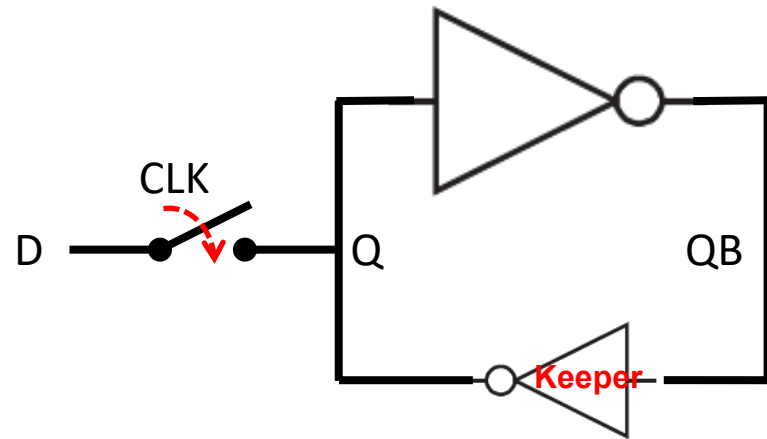
Dynamic Latch



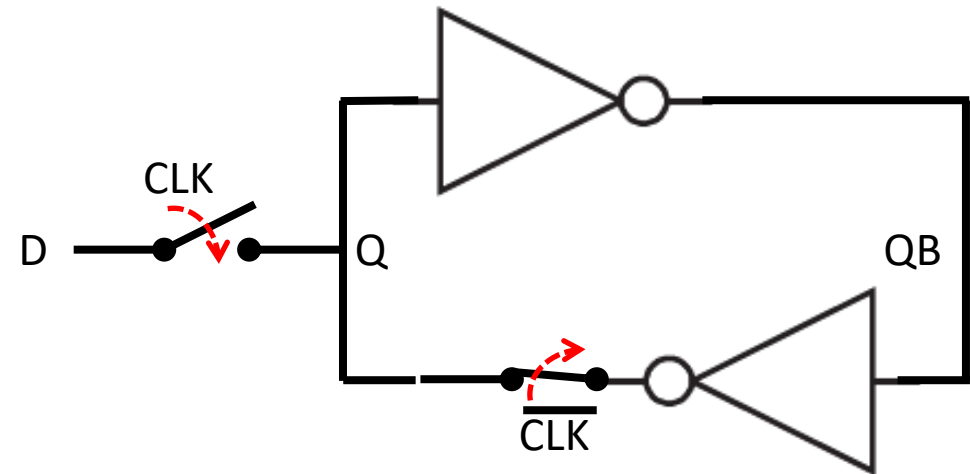
Static Latch

Ratioed vs. Non-Ratioed Latch

- **Writing to the latch involves overriding its internal state**
 - **Driver must prevail** over the internal keeper
- **Ratioed latch: strong driver overrides a weak keeper**
 - Sensitive to drive strength of the components
- **Non-ratioed logic: deactivate keeper while writing**



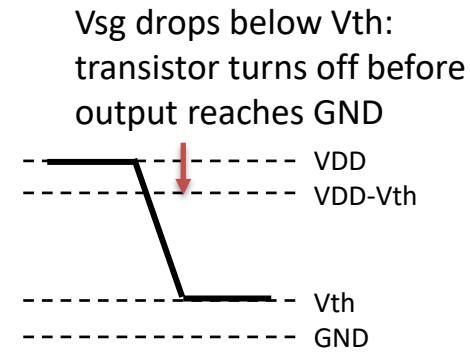
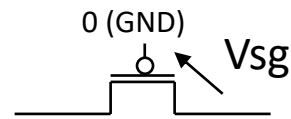
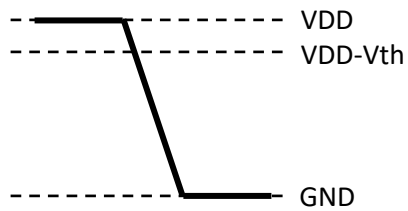
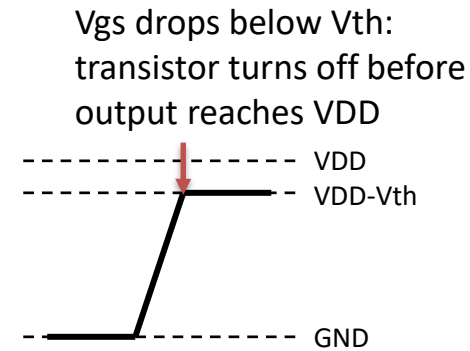
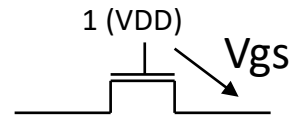
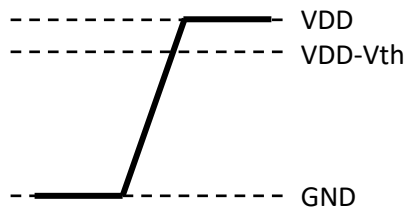
Static
Ratioed
Latch



Static
Non-ratioed
Latch

Disconnecting the Feedback Driver

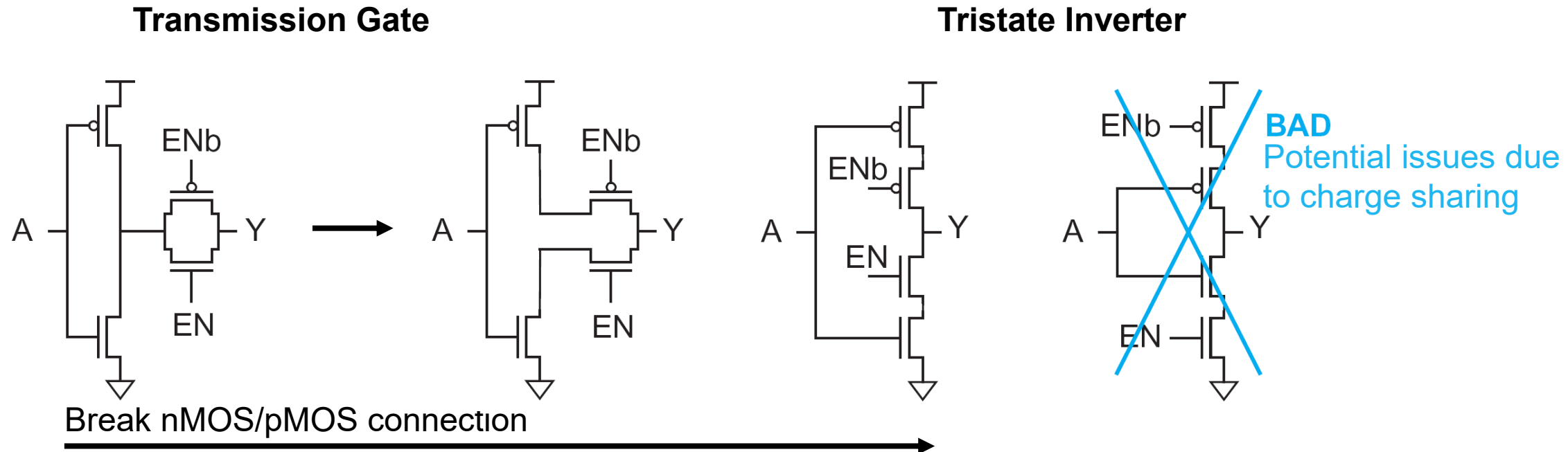
- Using a series transistor as a switch
- Which polarity to use: nMOS or pMOS → **both not very well suited...**
 - nMOS can only pass a strong zero
 - pMOS can only pass a strong one



Combine nMOS and pMOS to achieve full swing output

Transmission (T) Gates and Tristate-Inverter

- Driving both strong '0' and '1' requires a "hybrid" nMOS/pMOS switch
- Two almost identical options:



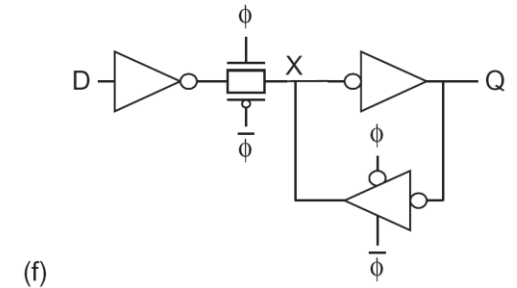
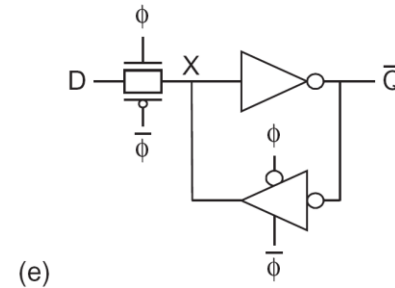
- Each part of the switch still used where it is most effective (almost no impact on on-resistance)
- Reduced output load

Robust Latches

- As **basic building blocks**, latches **need to be robust** and work in all conditions

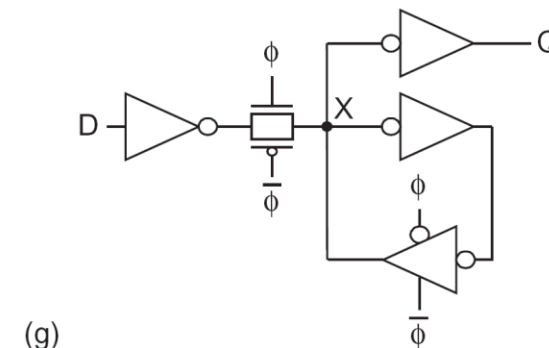
- Ensuring a **clean input interface** (capacitive load)

- Add extra input inverter to T-gate OR
- Use a tristate input inverter



- **Protecting the storage node (SN)**

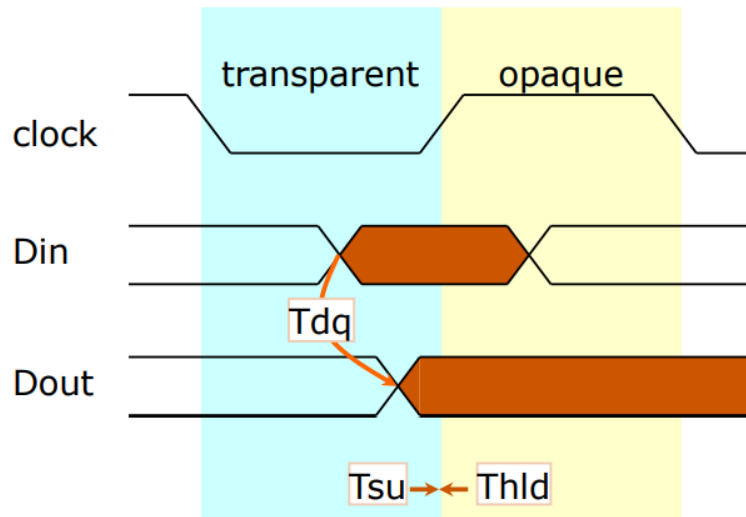
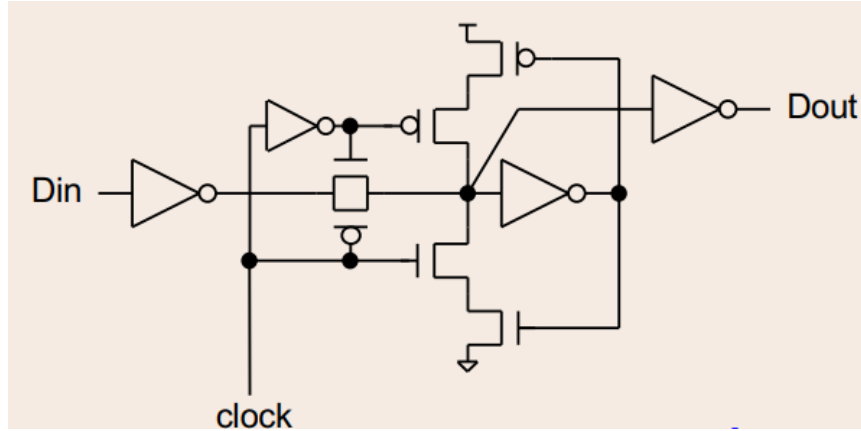
- Any spikes (e.g., from coupling or kickback) on the output (from external circuits) can alter the state
- Shield output from the storage node with an inverter



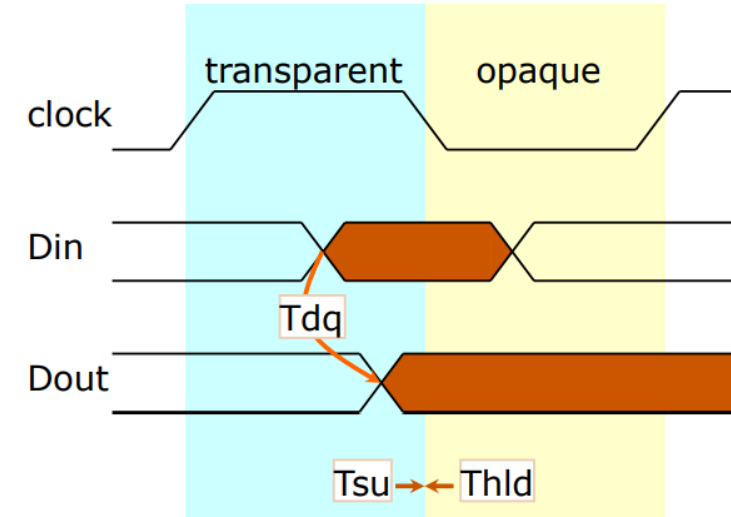
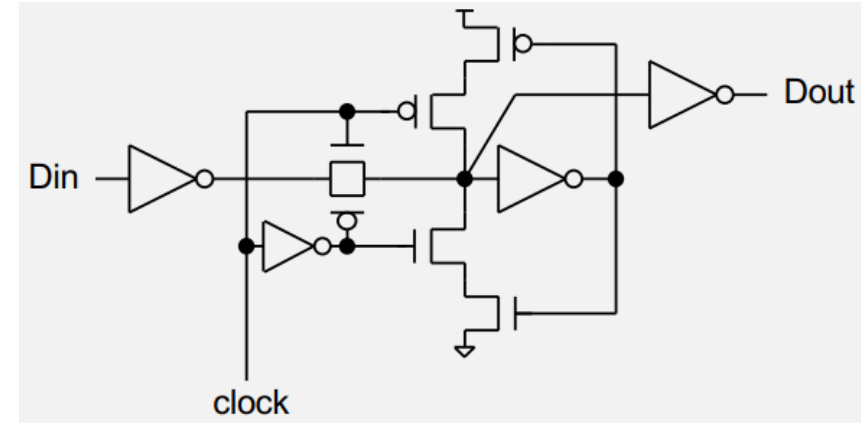
Latch Polarities

- Latches can be built with **different polarities**

Low-Transparent

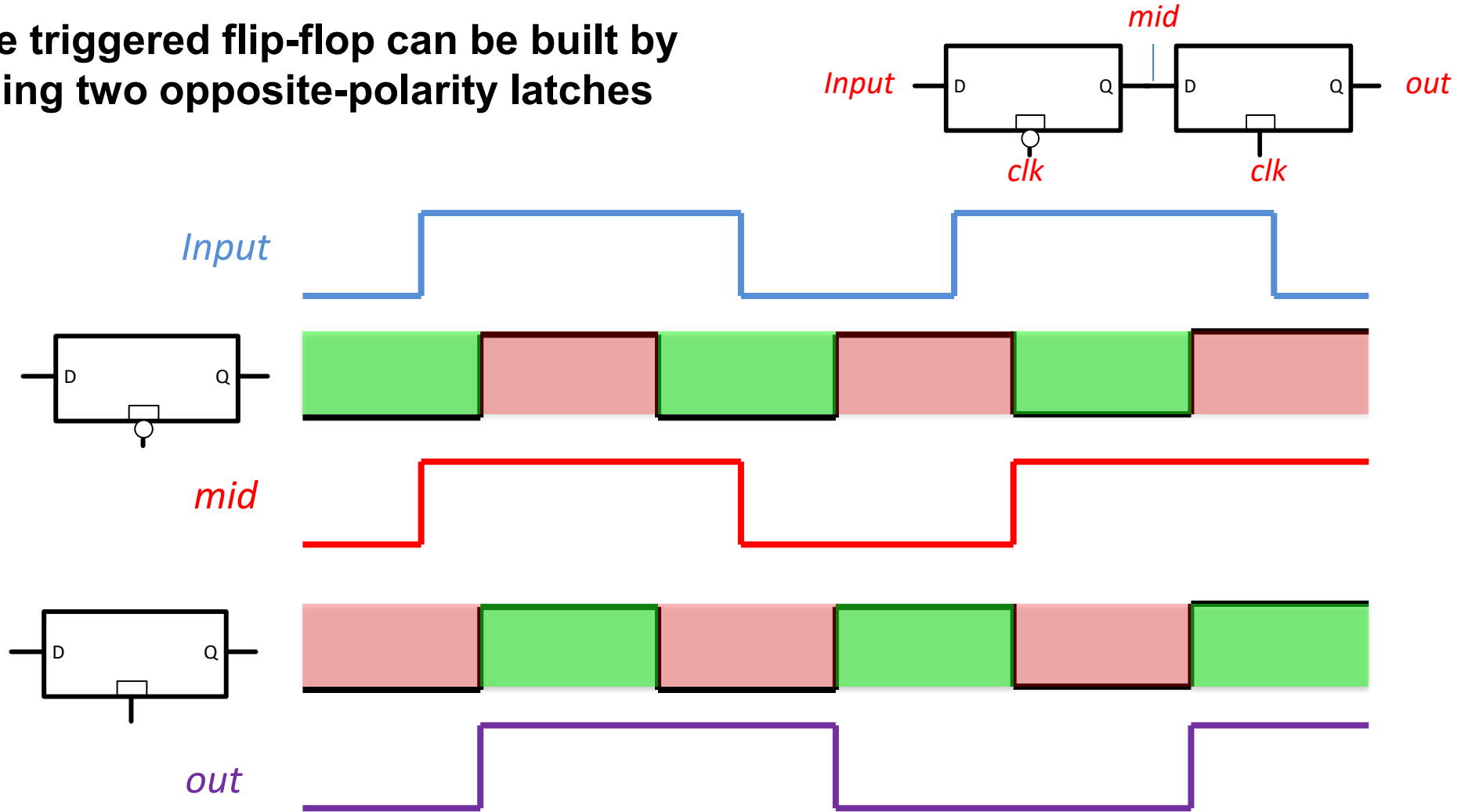


High-Transparent



Master-Slave Register (Flip Flop)

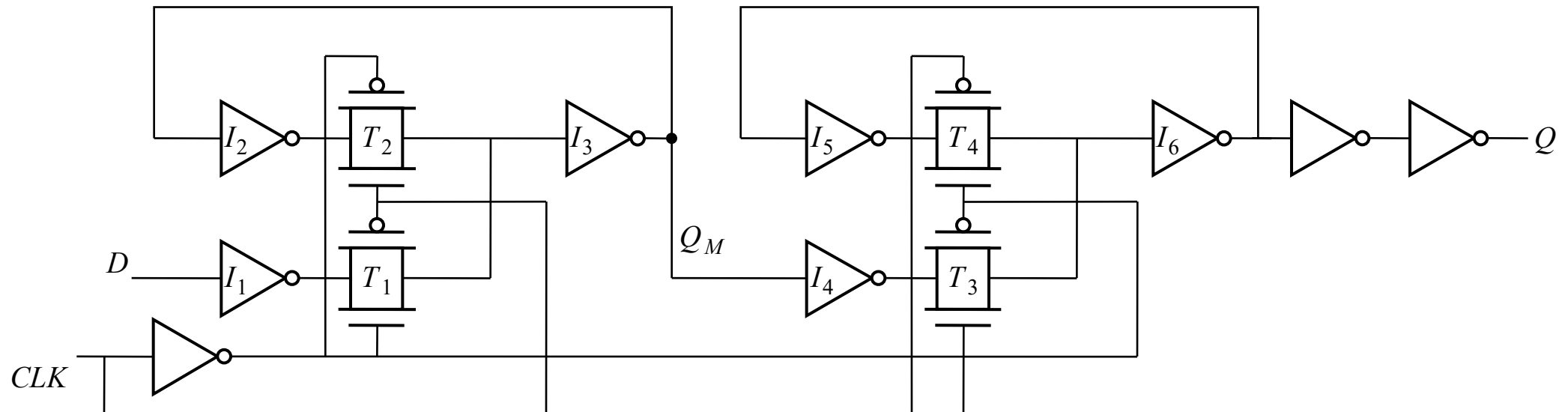
- An edge triggered flip-flop can be built by combining two opposite-polarity latches



Master-Slave Register

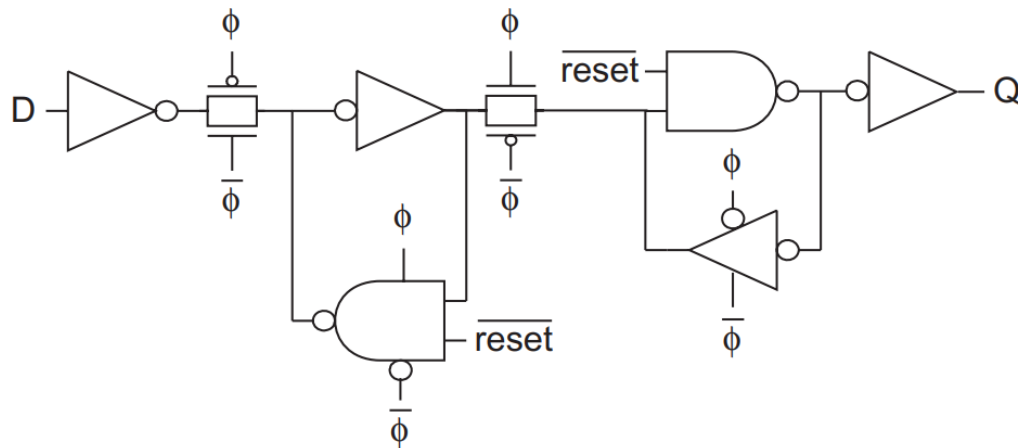
- **Basic ingredients**

- Two tristate-based pair of latches
- Output buffers to shield the SN
- Input buffer to present a capacitive load
- Output inverters to isolate the storage node

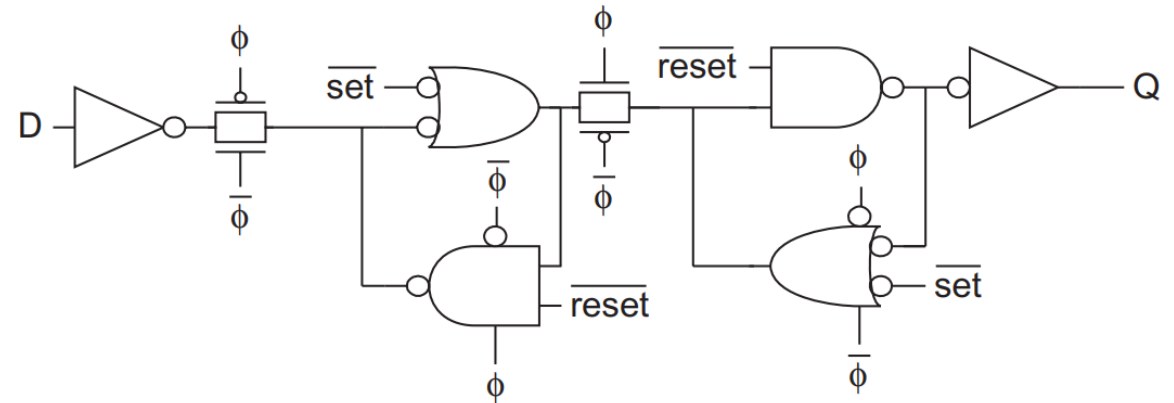


Set / Reset

- To reach a known initial state, **most FFs need to be set and/or reset**
 - Set/Reset refer to **ASYNCHRONOUS set/reset** (state change independent of clock)
 - Typically either set or reset (both is rare)
- Circuit design examples:
 - **Set/reset required on BOTH** master and slave latches



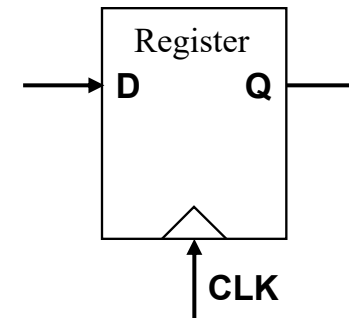
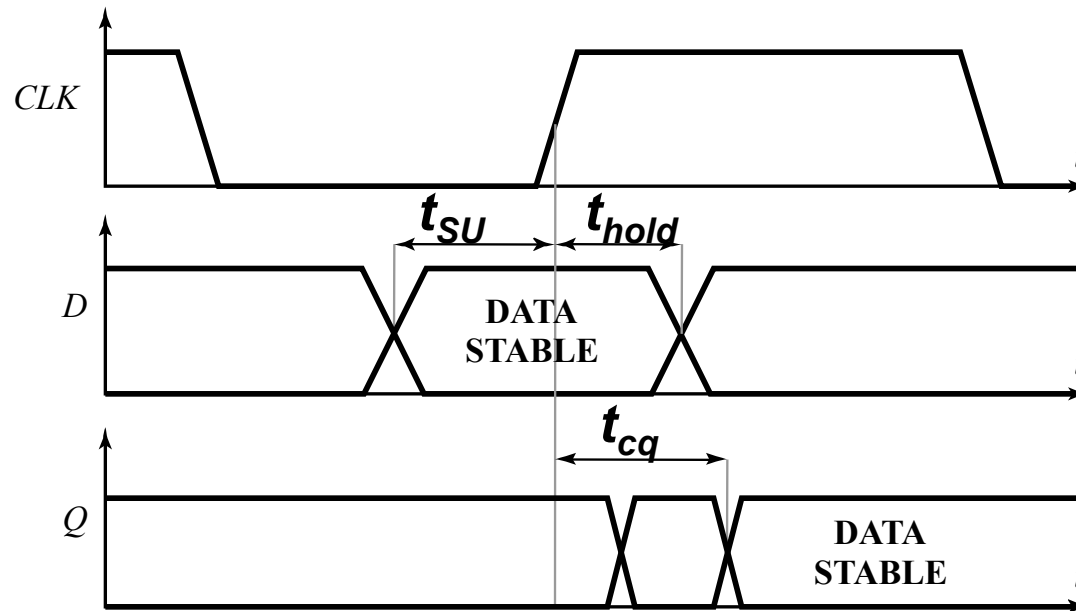
RESET
(low active)



SET and RESET
(low active)

Flip-Flop Delay and Timing Requirements

- As opposed to logic, **Flip-Flops have a delay and timing requirements**
 - Propagation delay t_{cq} : defined from CLK-input to Q-output
 - Setup time t_{su} : defined from D-input to CLK-input
 - Hold time t_{hold} : defined from CLK-input to D-input



Impact of Timing Requirements

- **Timing requirements for all register-to-register paths**
 - Path starts from the clock pin of a register and ends on the data pin of a register

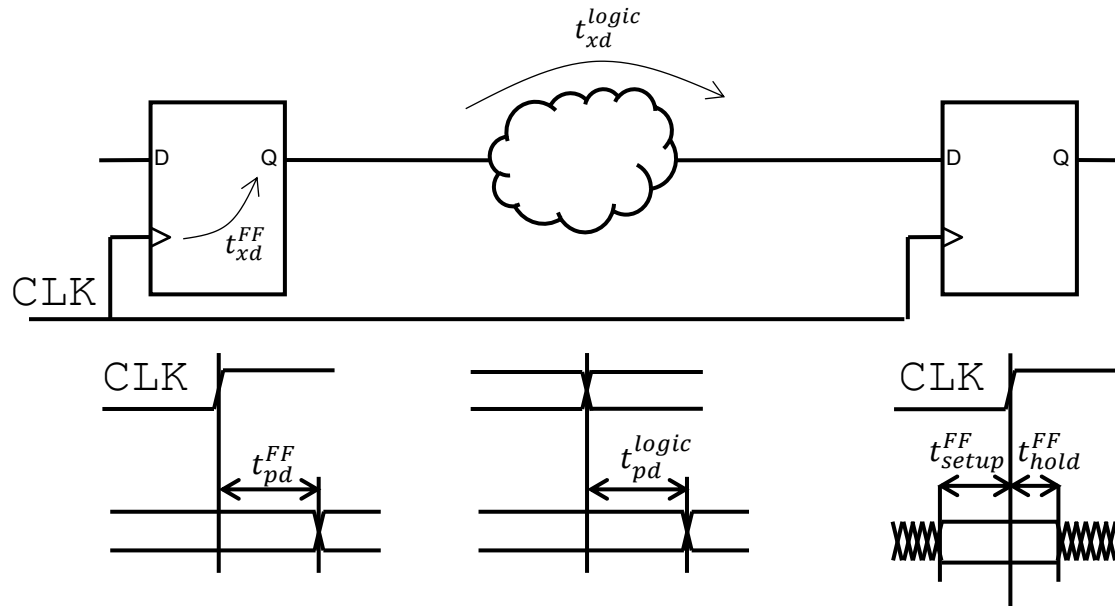
- **Setup condition:** latest arrival

$$\underbrace{t_{pd}^{FF} + t_{pd}^{logic}}_{t_{ss}^{max}} < t_{clk} - t_{setup}^{FF}$$

Determines maximum frequency

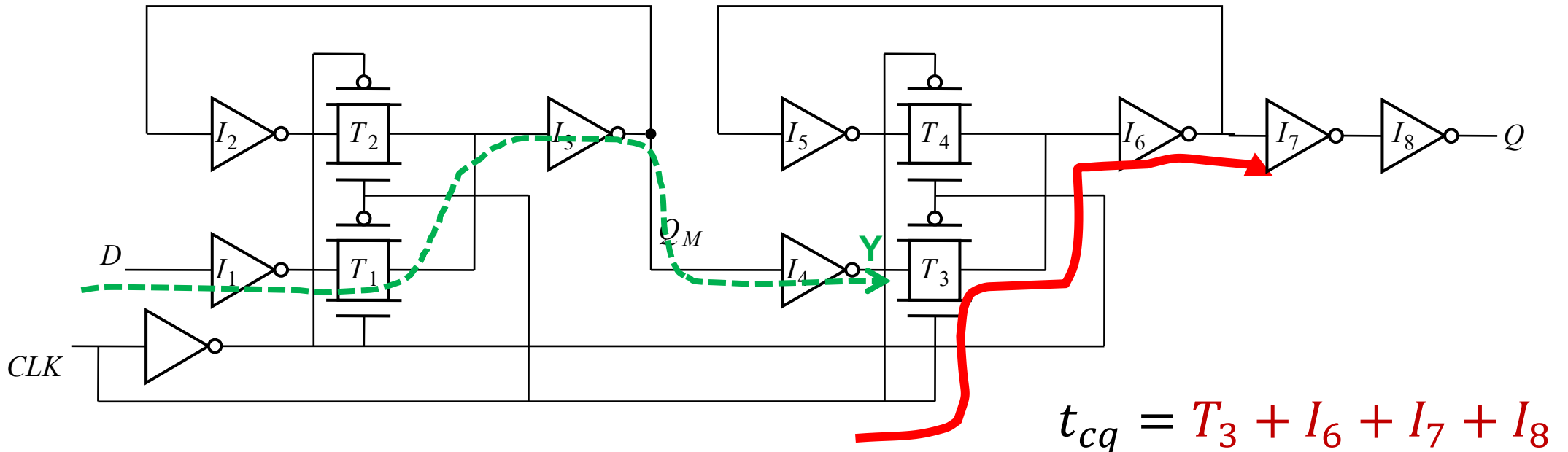
- Hold condition: earliest arrival

$$\underbrace{t_{cd}^{FF} + t_{cd}^{logic}}_{t_{ss}^{min}} > t_{hold}^{FF}$$



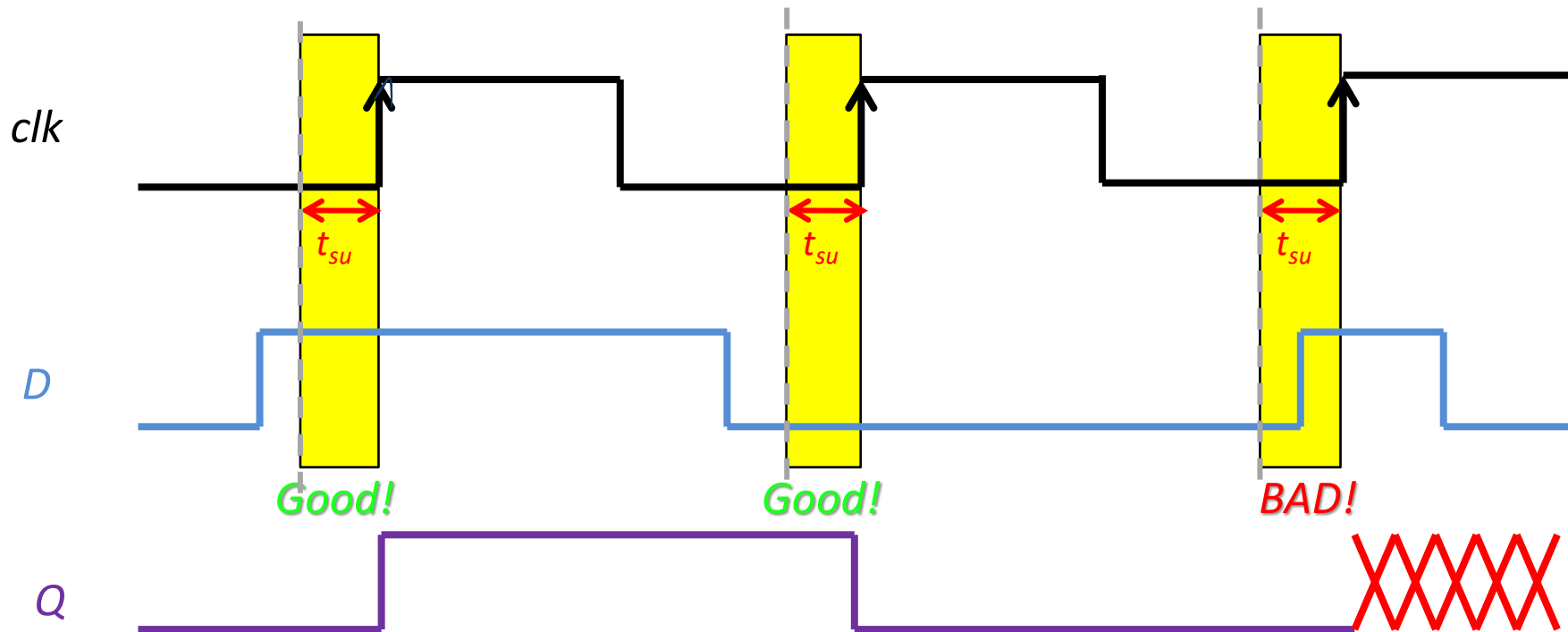
Propagation Delay Calculation

- **Output changes when slave latch turns transparent** after positive clock edge
 - New output already stable at node **Y (slave latch T-gate input)**
- **When clock rises, data still has to propagate through pass gate and inverter**



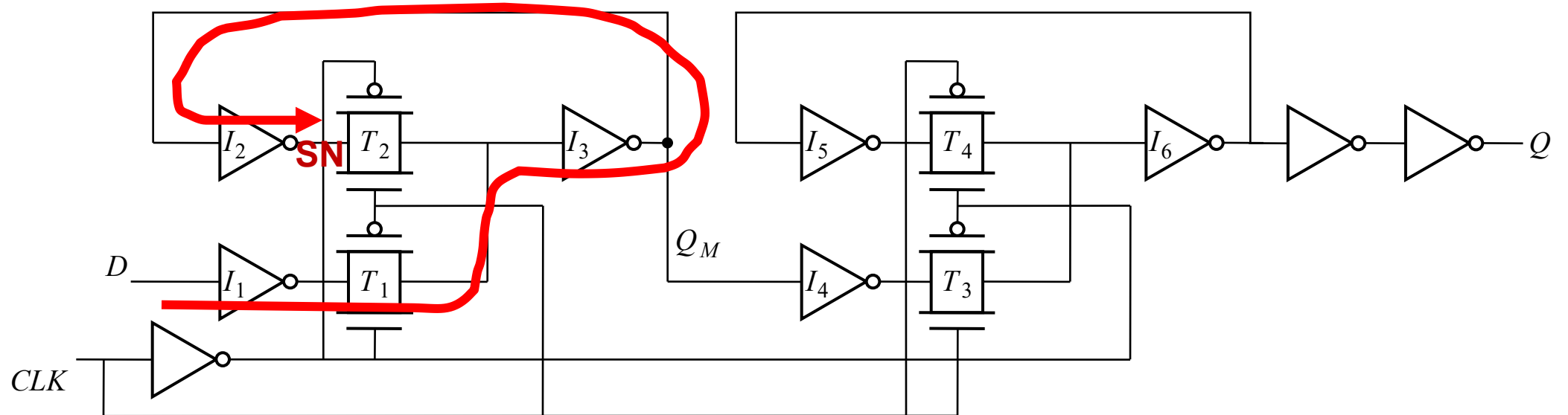
Setup Time Definition

- **Setup time is the time the data has to arrive *before* the clock to ensure correct sampling**



Setup Time Calculation

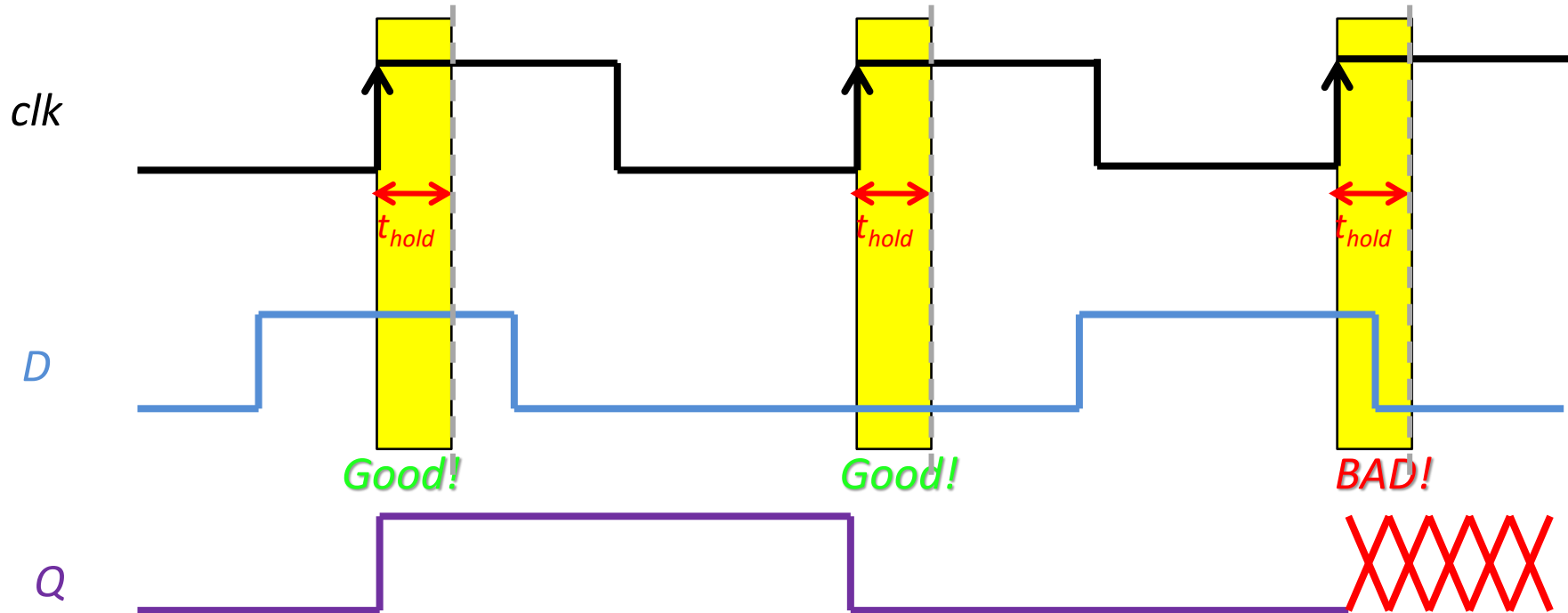
- **Master latch closes on positive clock edge**
 - Feedback loop of the **latch SN** must be stable at the new value before opening
- **Before the clock edge, data should have propagated to SN to avoid restoration of the previous state**



$$t_{su} = I_1 + T_1 + I_3 + I_2 = T + 3I$$

Hold Time Definition

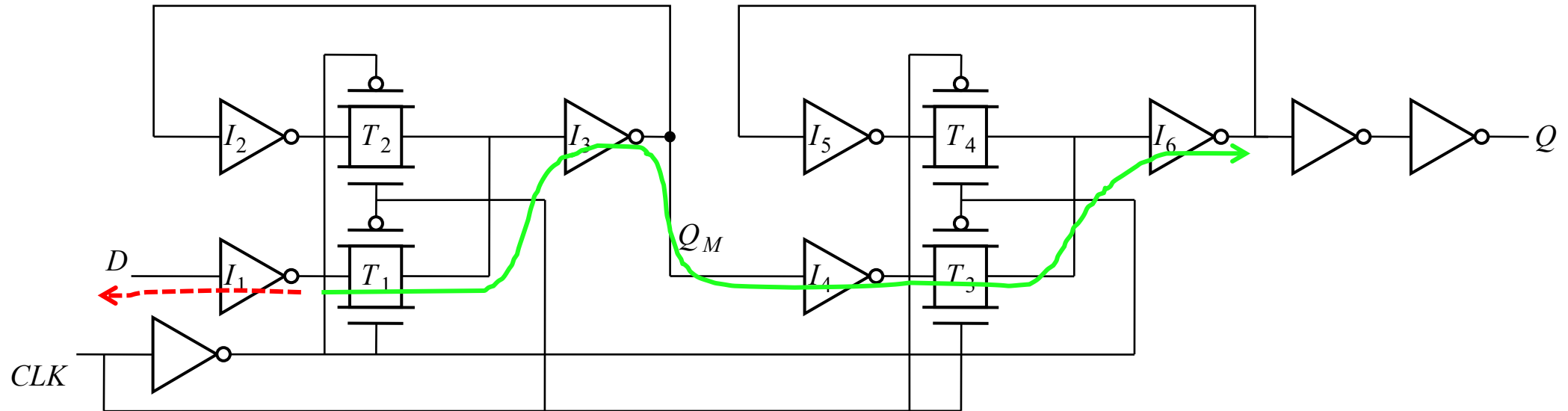
- Hold time is the time the data has to be stable *after* the clock to ensure correct sampling.



- Often (optimally), Hold Time is *negative*!

Hold Time Calculation

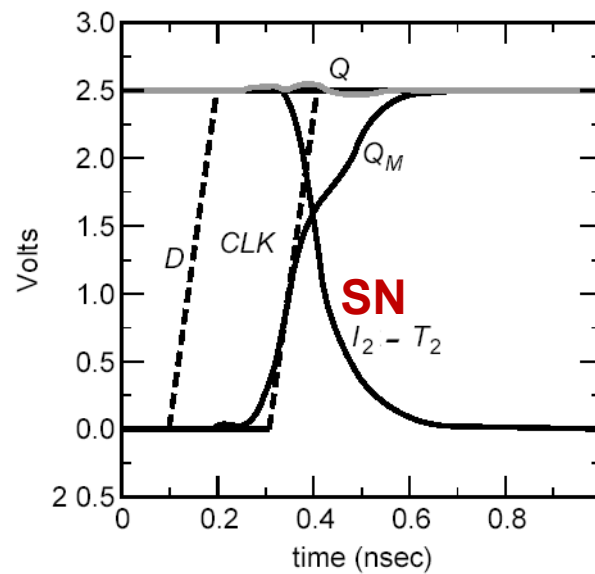
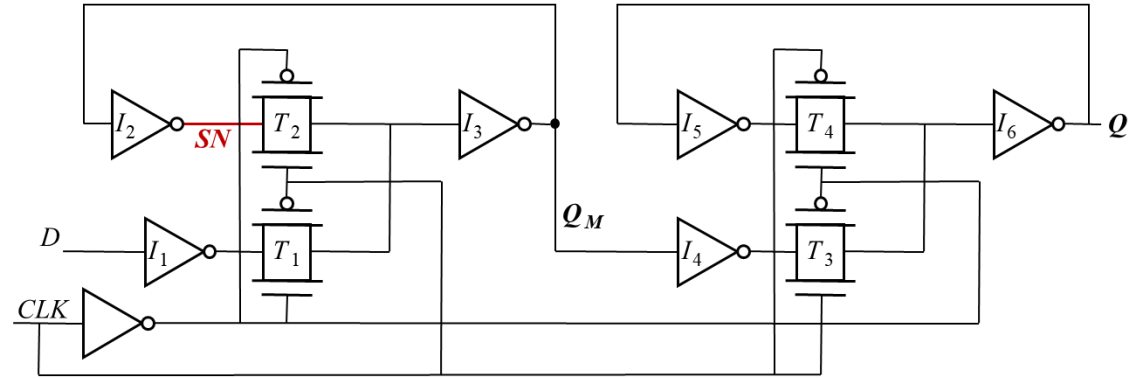
- **Master latch closes on positive clock edge**
 - SN must be stable until driving T-gate closes
 - Additional delays in the data path help to keep SN even after the input changes
- **The hold time can be negative**



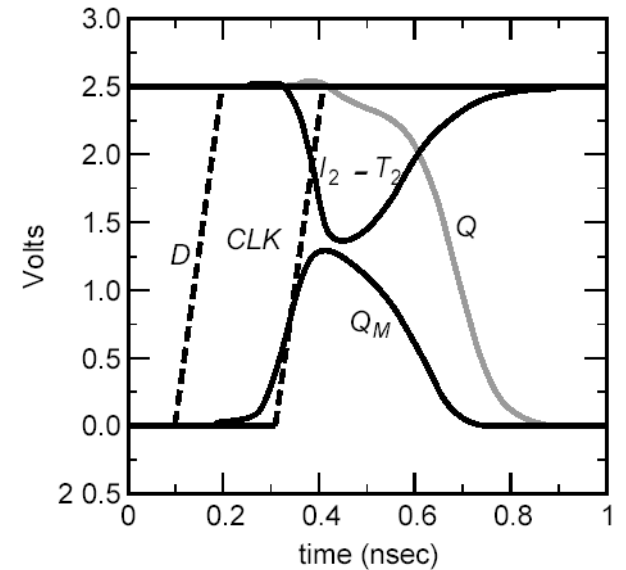
$$t_{hold} = -I_1$$

Impact of Setup Violations & Simulation

- **Example** for setup violation
 - SN: storage node (inverted)
 - QM: output of the master latch
- We obtain the **setup time** of the register using **SPICE simulations**, by progressively skewing the input with respect to the clock edge until the circuit fails



(a) $T_{\text{setup}} = 0.21 \text{ nsec}$

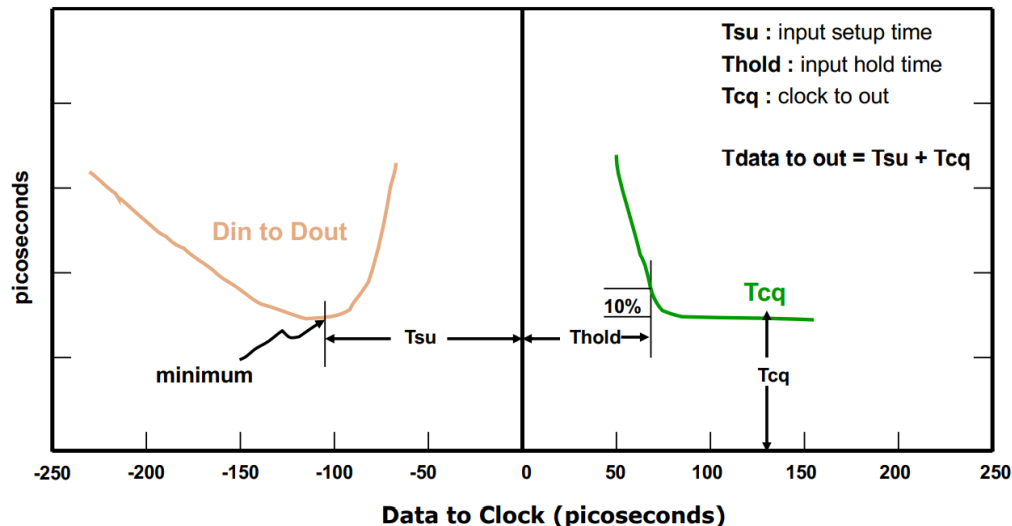
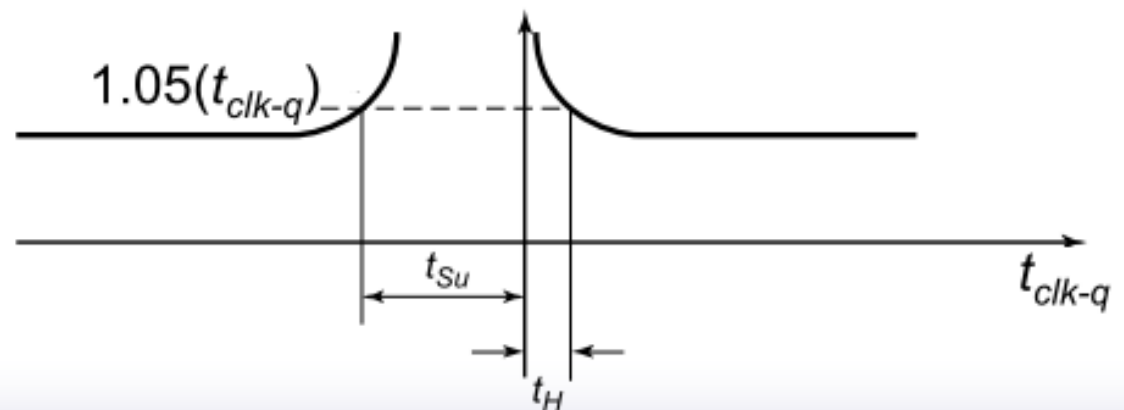
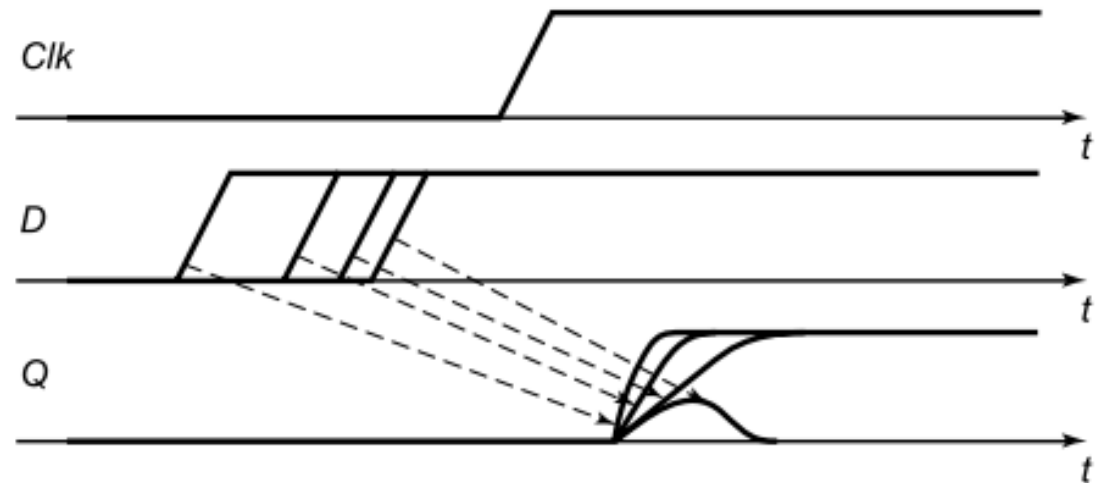


(b) $T_{\text{setup}} = 0.20 \text{ nsec}$



Impact of Marginal Setup Condition

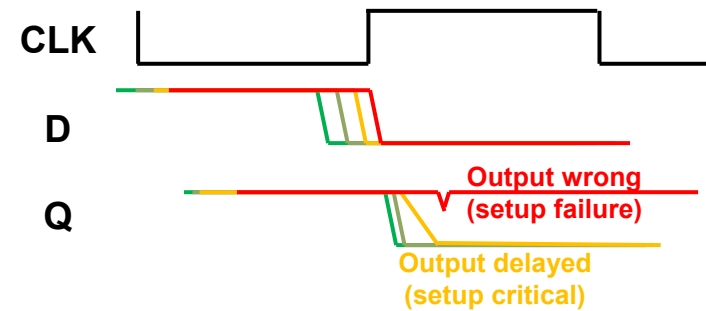
- **Setup violations do not always cause a complete failure (error)**
 - Marginal triggering leads to increase in the propagation delay before failing
 - Timing models do not represent this case properly
 - Constraints are for accuracy to ensure timing analysis remains valid



Simulation Based Setup/Hold Characterization

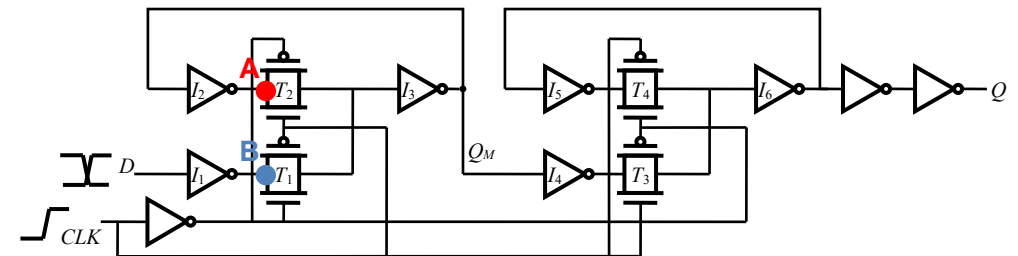
- **Setup/hold can not be measured directly** (requirements rather than delays)
- **Two options to bound these requirements**

1. Brute force simulations (trial and error) with pass fail constraint based on correct output or clk->Q delay constraint



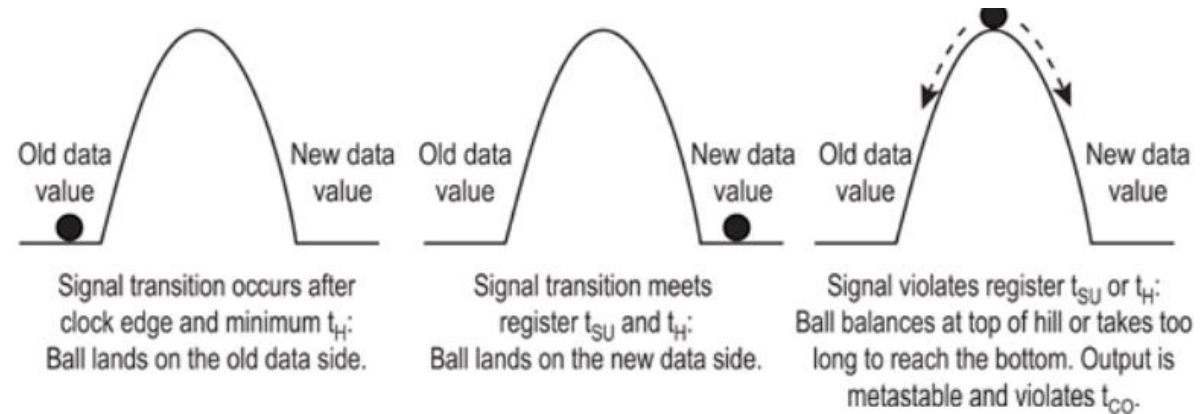
2. Conservative constraint based on delays of data and clock to internal nodes to ensure sufficient margins for proper operation

- Setup: **A** must be stable (new value) before T_{gate} opens:
 $T_{\text{su}} = T(D \rightarrow A) - T(\text{CLK} \rightarrow T_2)$
- Hold: **B** must be stable (old value) until T-gate closes:
 $T_{\text{ho}} = T(\text{CLK} \rightarrow T_1) - T(D \rightarrow B)$



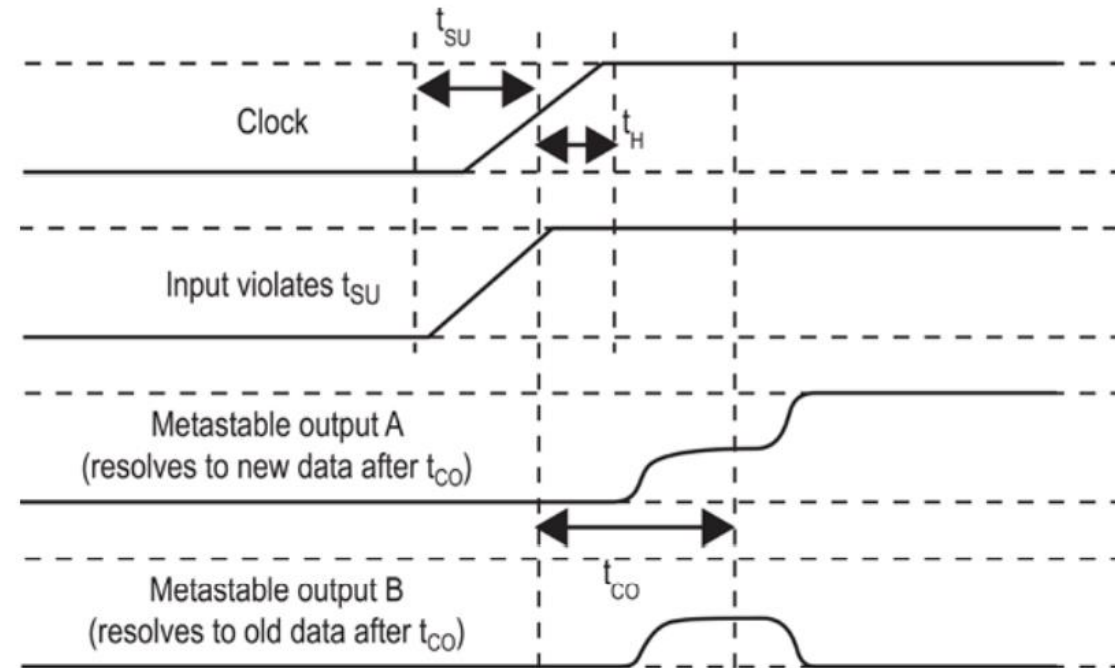
Metastability

- **Metastability:** third, **instable state** in bi-stable circuits



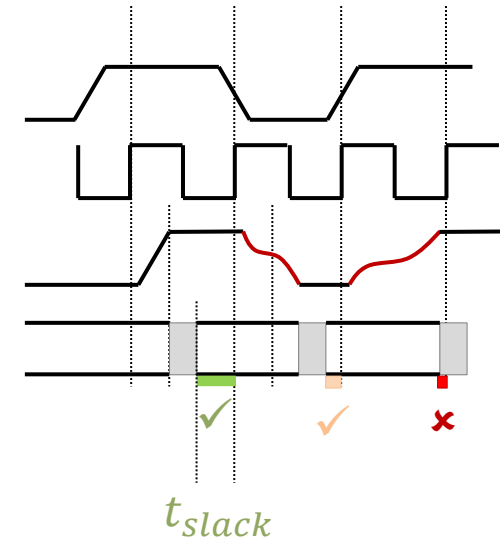
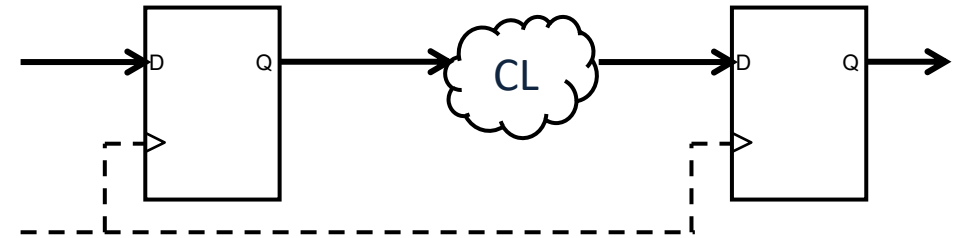
- **Metastability can** happen when violating setup/hold times

- Metastability is a temporary phenomenon and **resolves by itself after some time**
- Time to resolve must be considered a **random** variable (uncertain)



Metastability Failure Mechanism

- Time available to resolve a metastability depends on the available **margin S(slack)** with no metastability t_{slack}
- Any **metastability reduces** this **timing slack**
- If **no slack remains** (zero or negative slack), **timing errors occur in the next flip-flop**
 - Circuit no longer operates correctly (FAILURE)



Mean-Time-Between-Failure (MTBF)

- Since metastability duration varies, not every metastability leads to an error
- **Mean-Time-Between-Failures (MTBF)** provides an estimate of the reliability

- **The MTBF depends on**

- Distribution of the metastability duration
- The available timing slack t_{slack}
- How often a potentially metastable data input signal toggles f_{DATA}
- How often the data input signal is samples (i.e., the sampling clock) f_{CLK}
- Some empirically determined constants that depend on process, operating conditions, circuit, ... : T_0, τ_s

Failures per second

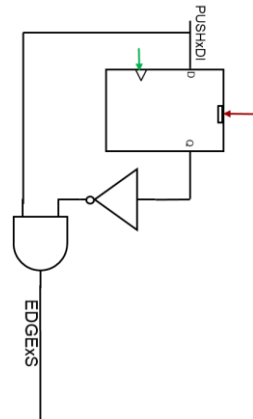
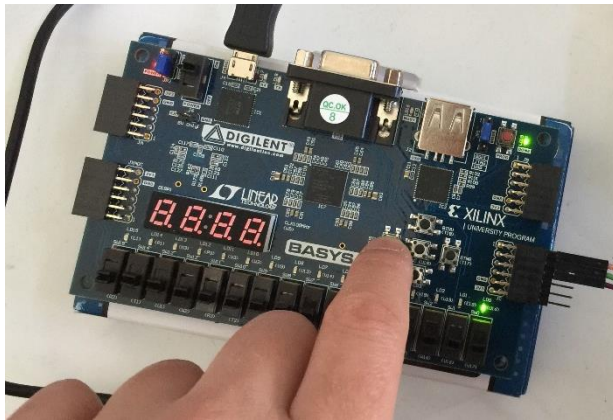
$$P_{failure} = T_0 \cdot f_{DATA} \cdot f_{CLK} \cdot e^{-t_{slack}/\tau_s}$$

$$MTBF = \frac{e^{t_{slack}/\tau_s}}{T_0 \cdot f_{DATA} \cdot f_{CLK}}$$

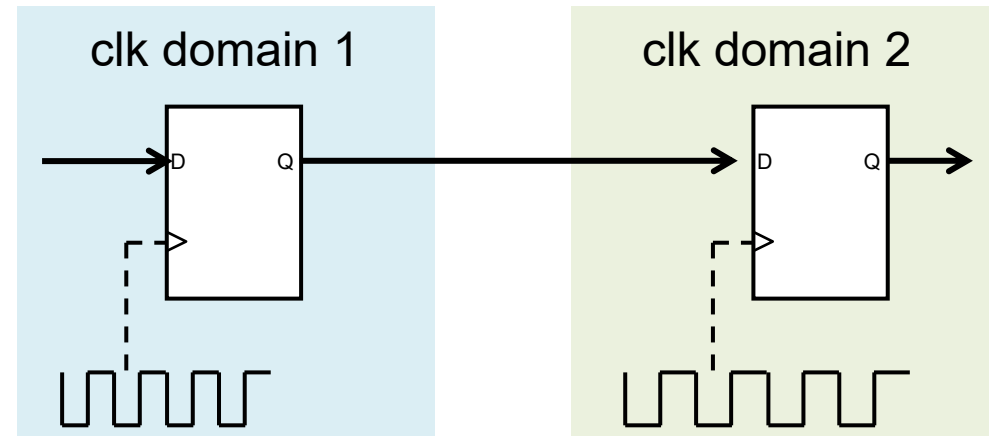
Reasons for Metastability Failures

- **A well-built synchronous circuit with the right clock should never face metastability issues** (ensured by static timing analysis)
- **Unfortunately, still sometimes inputs are not synchronized to their clock**
- Examples:

Example 1:
asynchronous primary inputs
(buttons or low-frequency inputs from other chips)



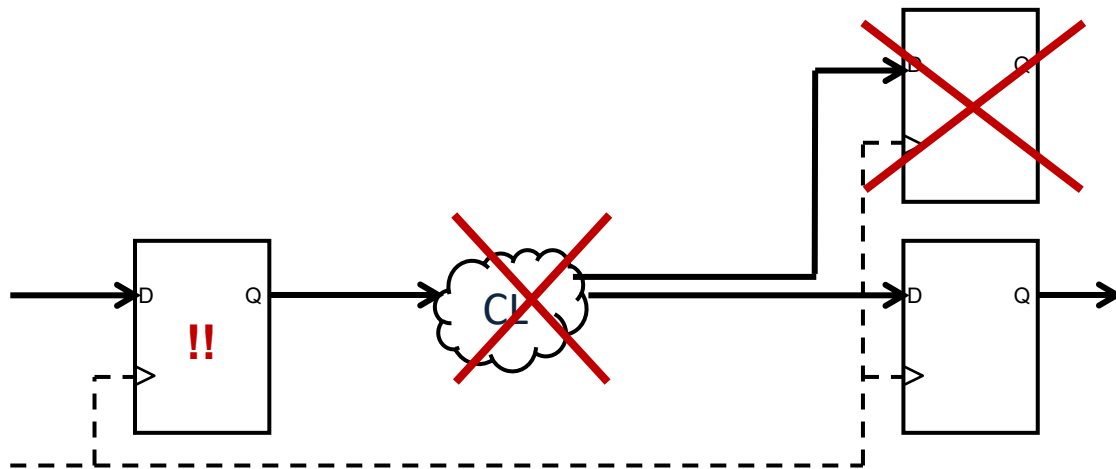
Example 2:
signals between asynchronous clock domains



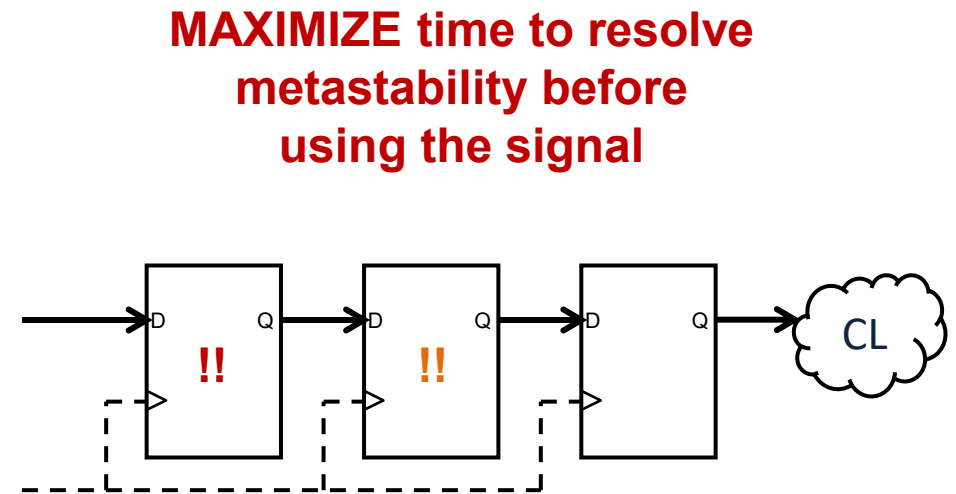
Measures to Reduce Impact of Metastability

- **If metastability can not be avoided we need to reduce its impact**
- **Three** main **principles** to reduce impact of metastability (reduce risk of failure)

Avoid any logic in potentially metastable signals



NO FANOUT: only impact one subsequent register



EE-429

Fundamentals of VLSI Design

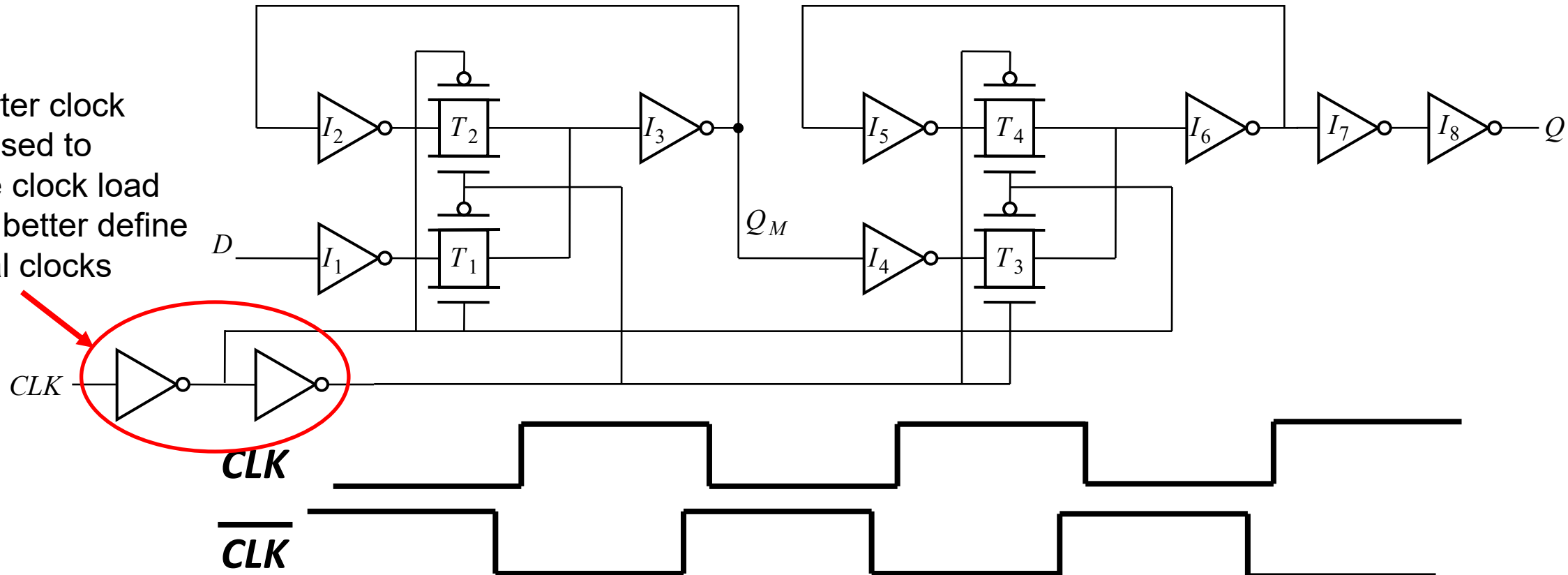
More Sequential Elements

Andreas Burg

The Clock Overlap Problem

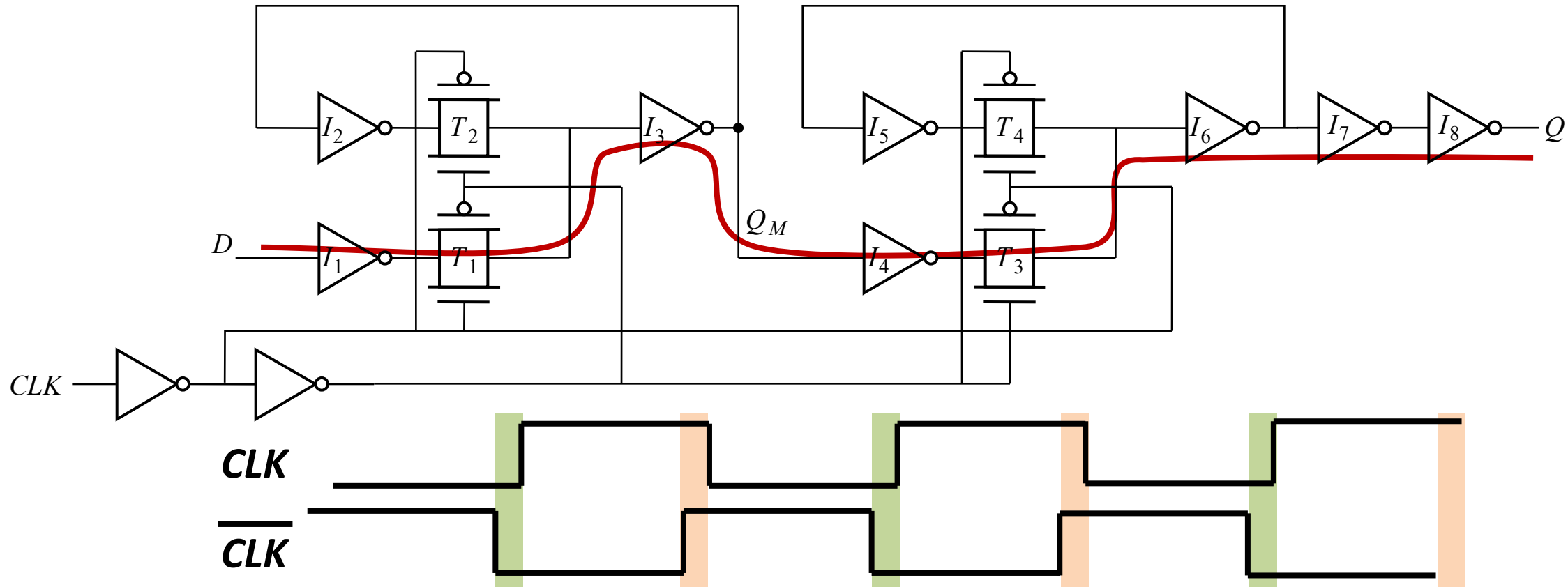
- **Master/Slave FlipFlops use both CLK and $\overline{\text{CLK}}$, which is generate from CLK**
 - Generating $\overline{\text{CLK}}$ from CLK usually involves a delay
 - Locally generating $\overline{\text{CLK}}$ may cause this delay when 2 inverters are used

2 inverter clock input used to reduce clock load and to better define internal clocks



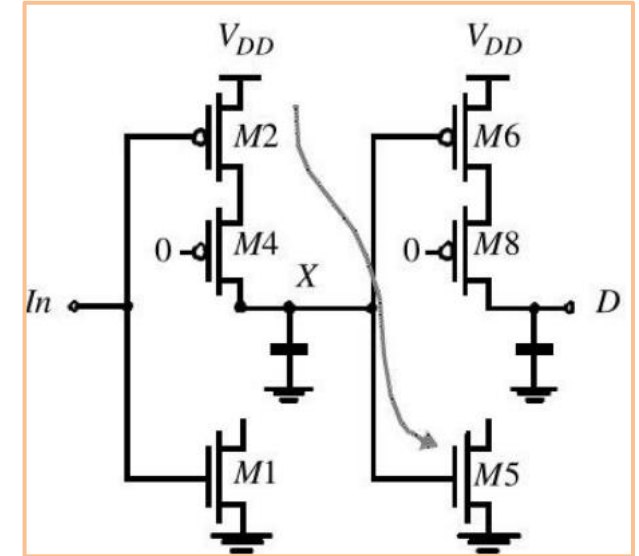
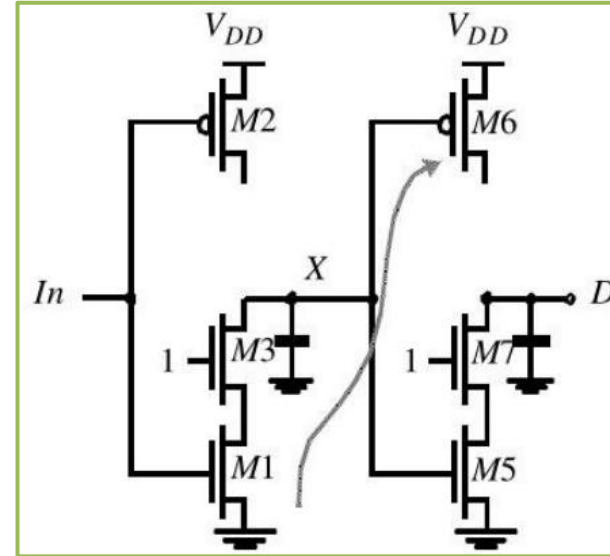
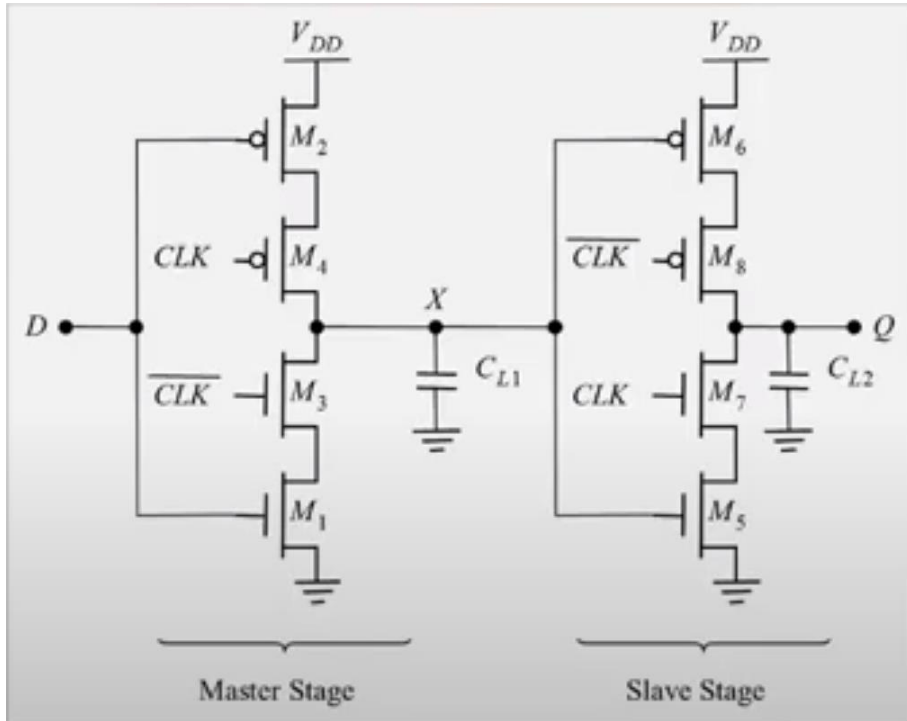
The Clock Overlap Problem

- Delay of \overline{CLK} leads to **clock overlap on both edges**
- During the overlaps both Master and Slave latches are briefly open
 - Signal can pass directly from input to output **causing a race-condition**

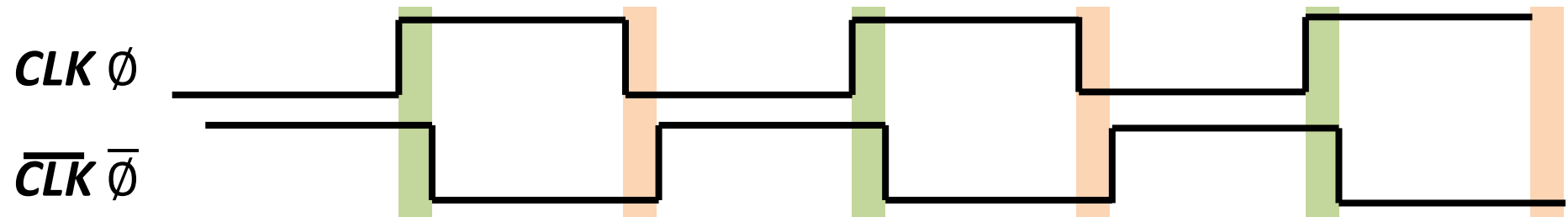


Solution 1: Clocked CMOS (C²MOS)

- **Master/Slave-FlipFlop from dynamic latches** avoids sensitivity to clock overlap

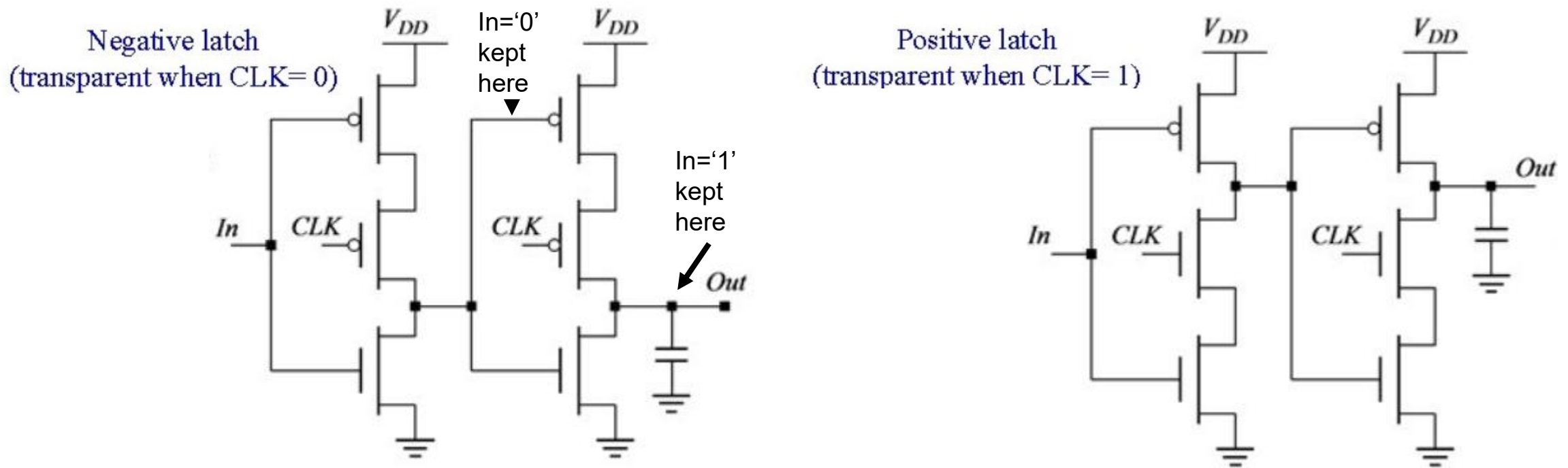


Used a lot by IBM



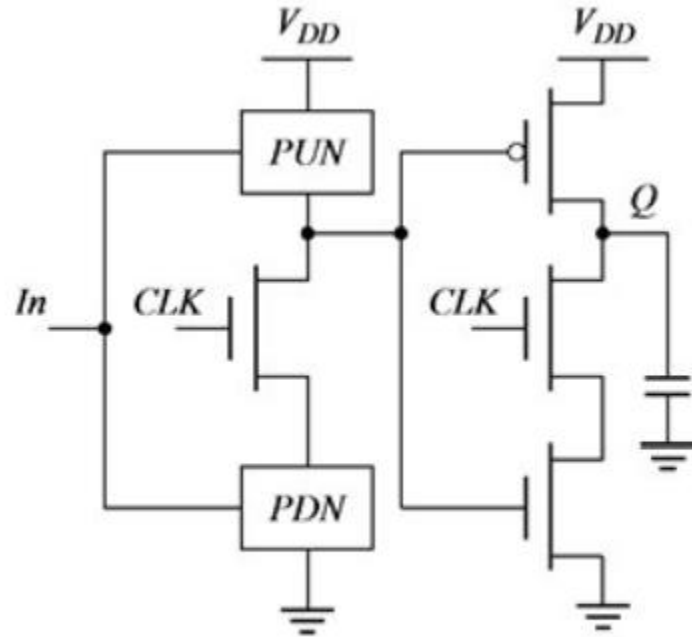
Solution 2: True Single Phase Clocked (TSPC) Latch

- **C²MOS still requires two clocks** a positive and an inverted one (overhead)
- **TSPC: different Master/Slave structures for different phases with same clock**
 - Two subsequent inverters that keep either a ZERO (high-transparent) or a ONE (low-transparent)
 - Input levels of '0' and '1' are kept on two different nodes

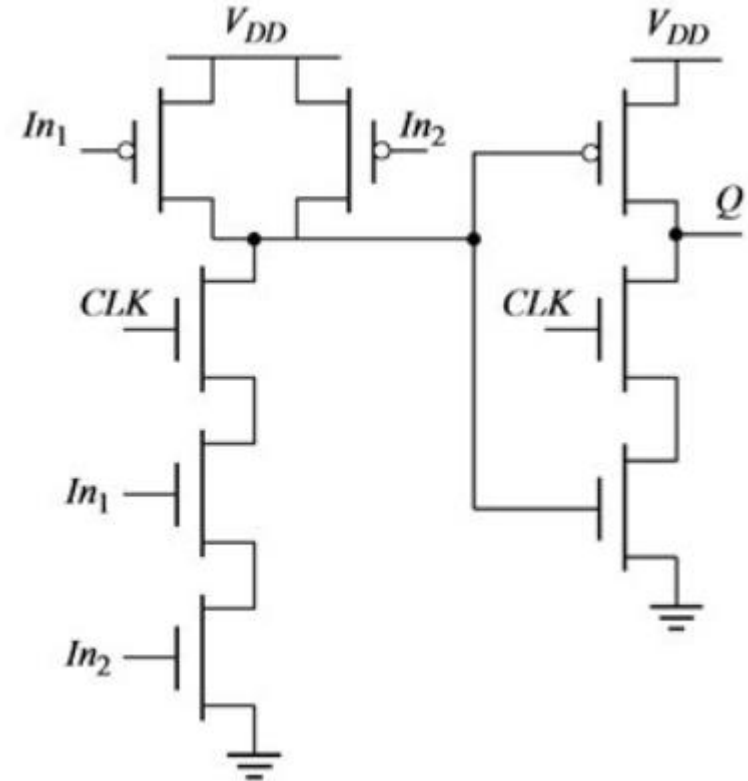


Solution 2: TSPC Latch with Integrated Logic

- **TSPC latches allow to** replace the initial inverter with any PMOS/NMOS network to realize an integrated logic function



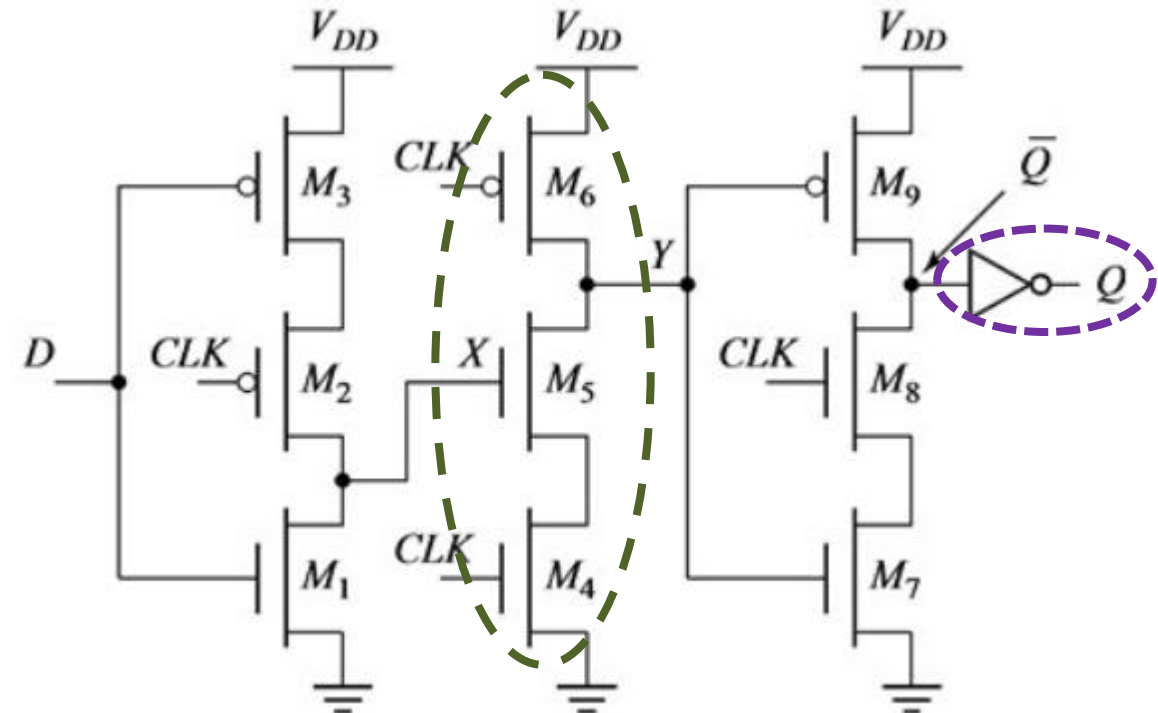
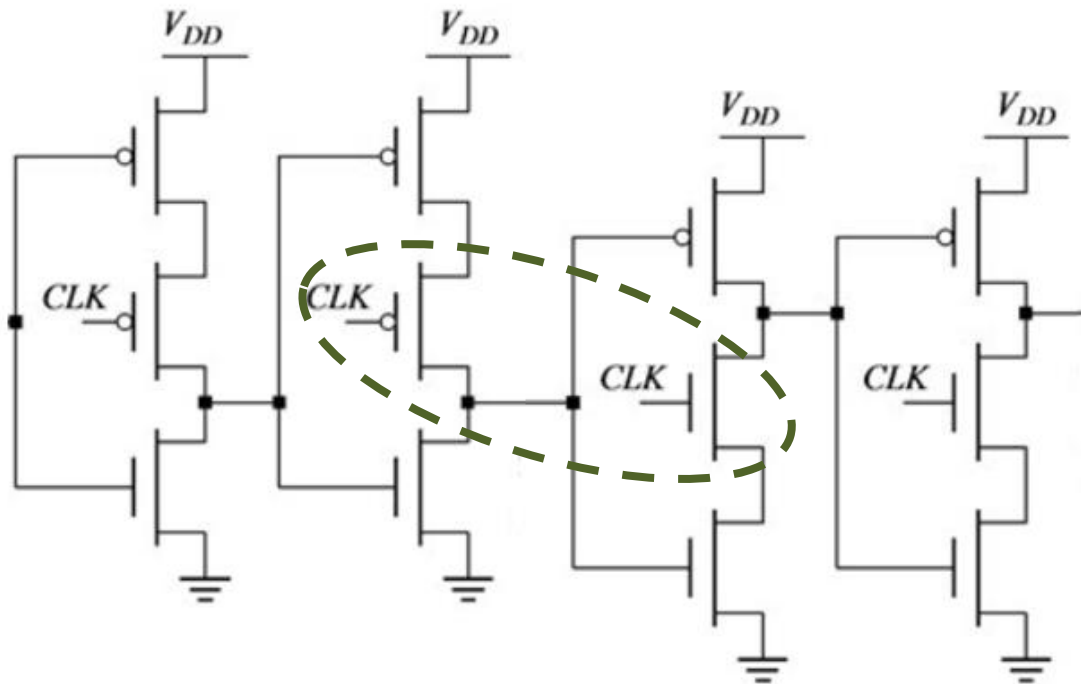
Arbitrary Logic in an TSPC Latch ('1' transparent)



Example: 2-input AND

Solution 2: TSPC FlipFlops

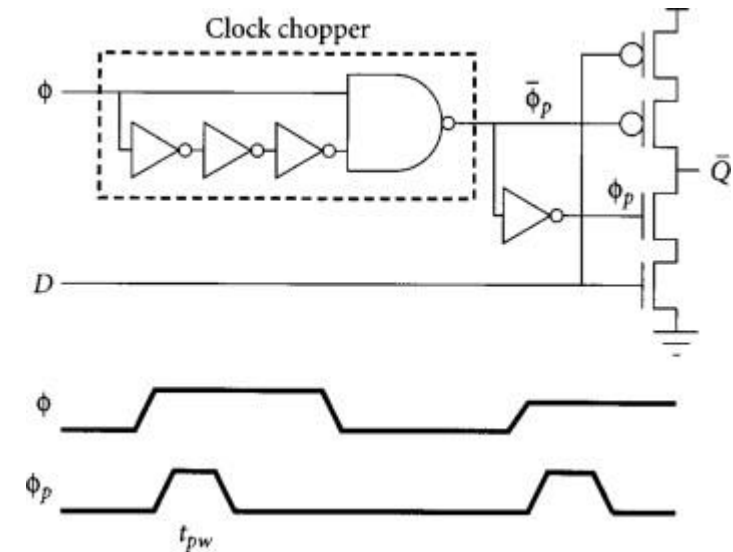
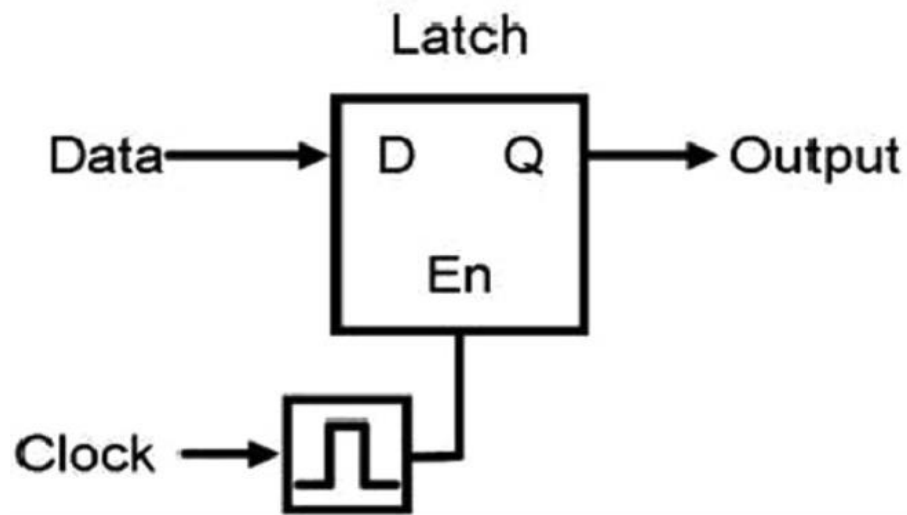
- TSPC FlipFlops are built by **two TSPC latches** in **Master/Slave** configuration
- **Two center-stages can be combined** to remove one stage
 - Results in an **inverted output**



Compact TSPC FF with shielded output

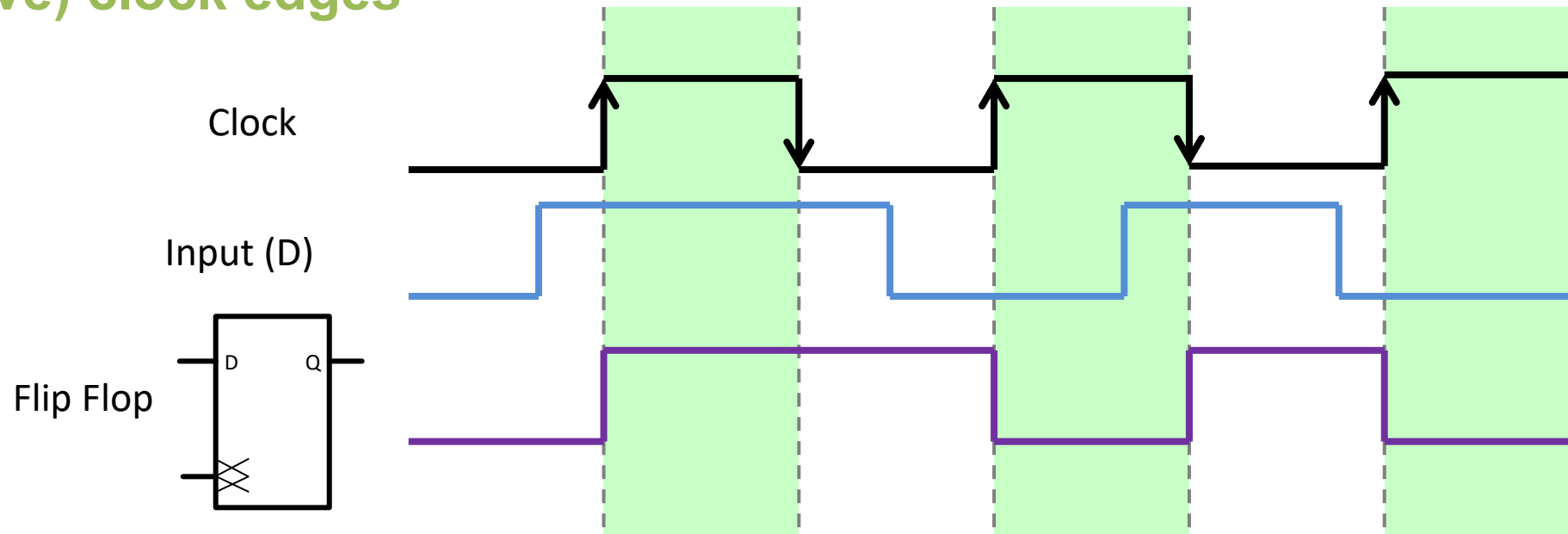
Solution 3: Pulsed (dynamic) Latch as FlipFlop

- **Build a FlipFlop from a latch that is triggered by a short pulse**
 - Pulse generator (dynamic EDGE detector) built from delay elements
- **Many different forms: static, dynamic, single and double-edge triggered**
- **Main issue: pulse duration is tradeoff between robustness and hold time**



Dual/Double Edge Triggered FlipFlops

- In single-edge (positive or negative) edge-triggered logic, one (the inactive) transition of the clock signal has no functional role
 - Every “operation” cycle requires two clock transitions => inefficient in terms of power
- **Solution:** dual-edge triggered FlipFlops store data on both (positive and negative) clock edges



Dual/Double Edge Triggered FlipFlops (cont.)

- Different realizations of dual-edge triggered FlipFlops are possible
- Most straightforward and most practical **implementation is based on two latches and a MUX**
 - Setup and hold times defined by a latch
 - No clock-overlap problem
 - Clock load is higher than for a simple single-edge triggered FlipFlop (power!!)
 - Need to avoid sneak-paths through the MUX between latches during switching

